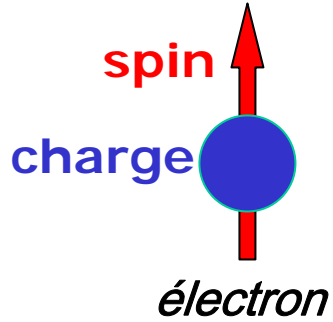
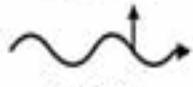


Présent et futur de la spintronique (LAAS, 17/12/08)



Influence of spin on conduction

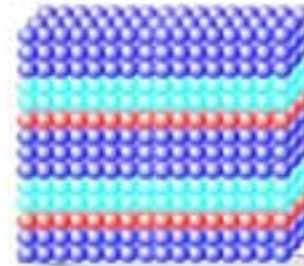
Spin up electron



Spin down electron



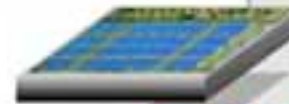
Magnetic nanostructures



Spintronics

GMR, TMR, etc...

Memory (M-RAM)



Read heads, sensors, etc.



Spin transfer :

- writing by electrical transport of magnetic information,
- microwave generation

spintronics with semiconductors,

molecular spintronics,

Single-electron spintronics, etc

Introduction :

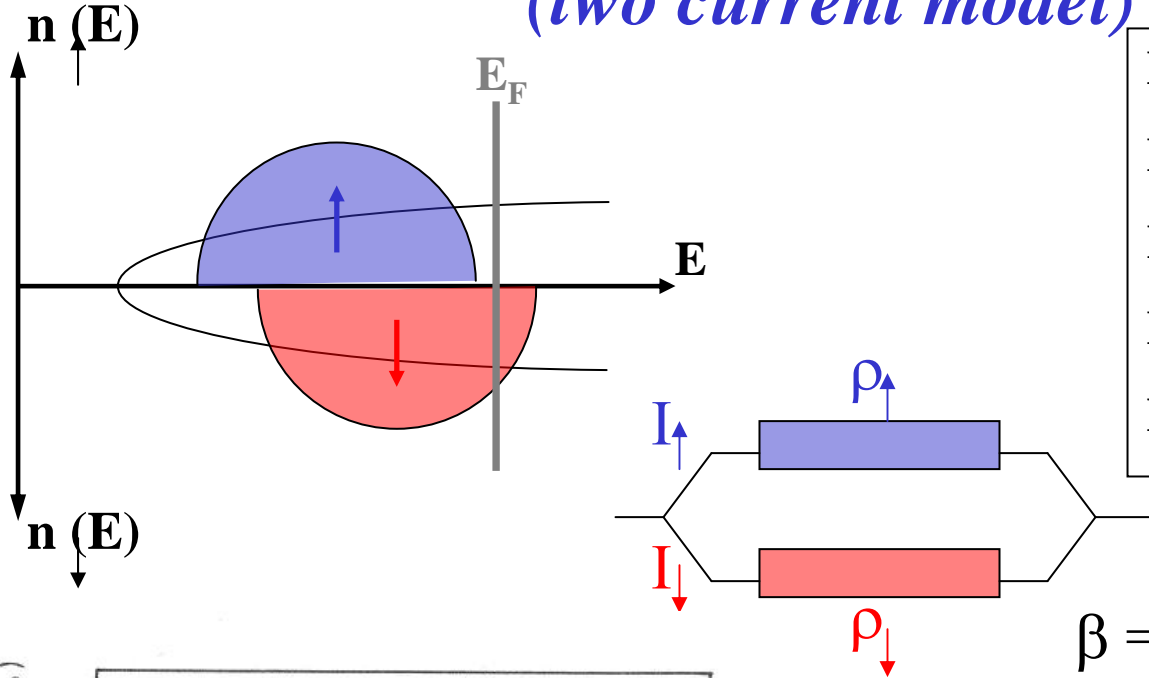
**Spin dependent conduction in
ferromagnetic conductors,**

Giant Magnetoresistance (GMR),

Tunnel Magnetoresistance (TMR)

Spin dependent conduction in ferromagnetic metals

(two current model)



Mott, Proc.Roy.Soc A153, 1936

Fert et al, PRL 21, 1190, 1968

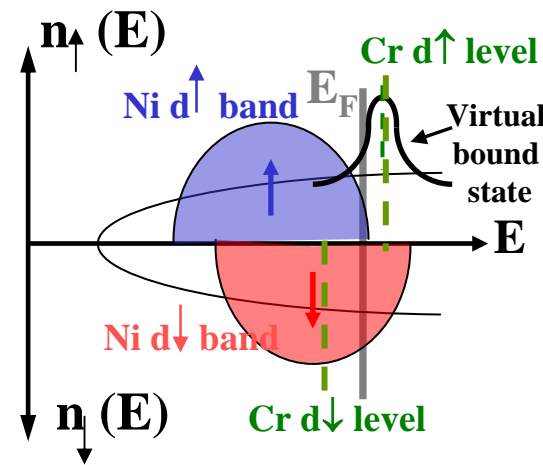
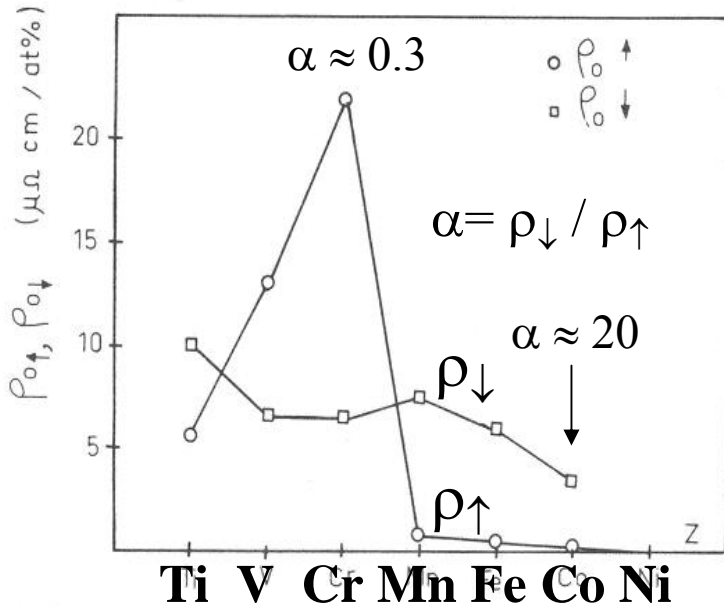
Loegel-Gautier, JPCS 32, 1971

Fert et al, J.Phys.F6, 849, 1976

Dorlejin et al, ibid F7, 23, 1977

$$\alpha = \rho_{\downarrow} / \rho_{\uparrow} \text{ or}$$

$$\beta = (\rho_{\downarrow} - \rho_{\uparrow}) / (\rho_{\downarrow} + \rho_{\uparrow}) = (\alpha - 1) / (\alpha + 1)$$



Mixing impurities A and B with opposite or similar spin asymmetries: *the pre-concept of GMR*

Example: Ni + impurities A and B (Fert-Campbell, 1968, 1971)

1st case

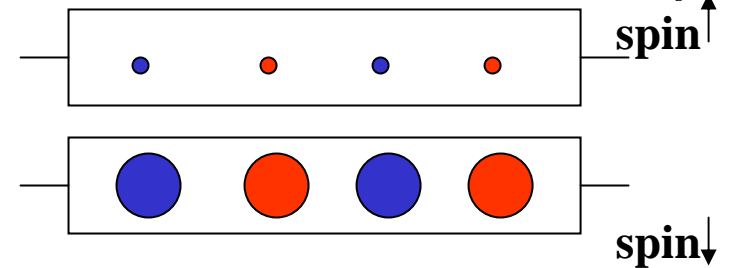
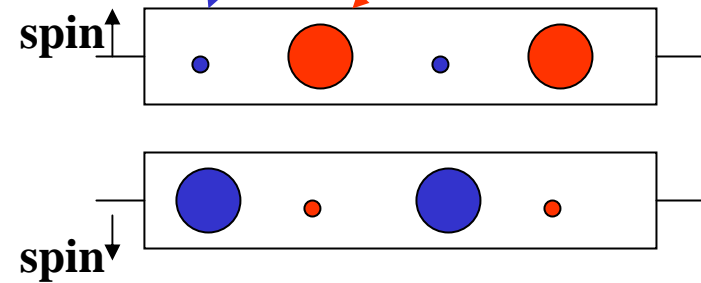
$$\alpha_A > 1, \alpha_B < 1$$

$$\alpha = \rho_{\downarrow} / \rho_{\uparrow}$$

2d case

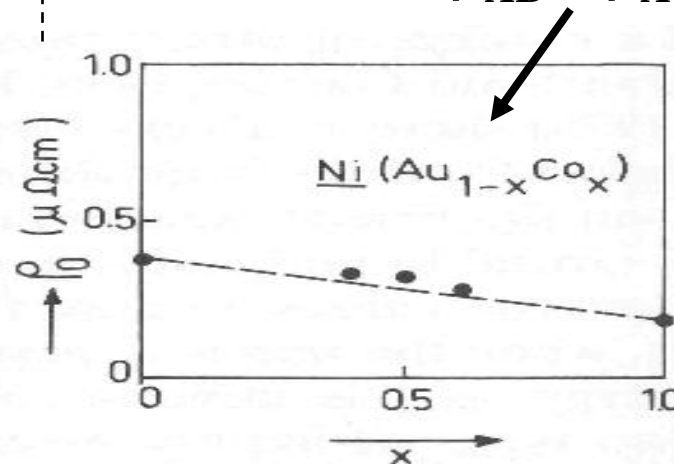
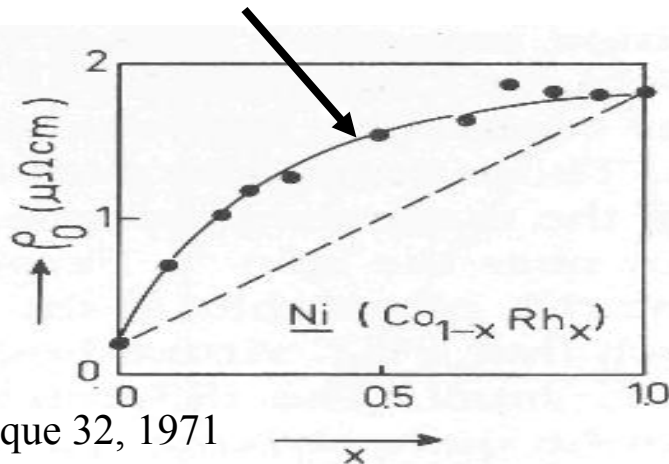
$$\alpha_A \text{ and } \alpha_B > 1$$

High mobility channel \rightarrow low ρ

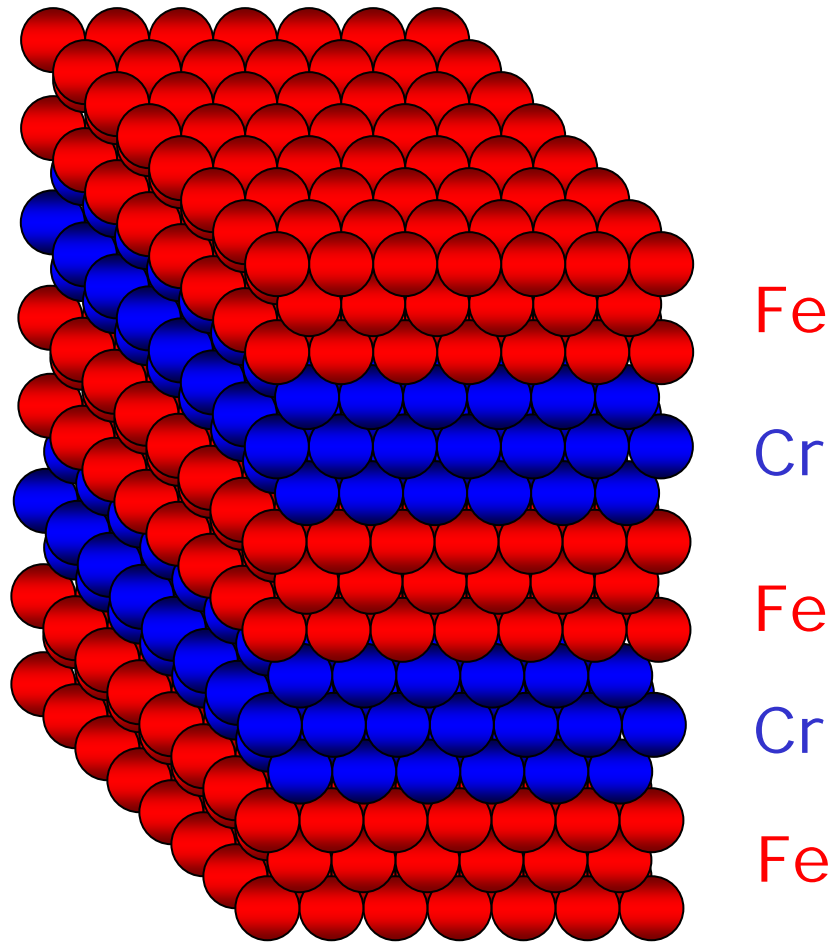


$$\rho_{AB} \gg \rho_A + \rho_B$$

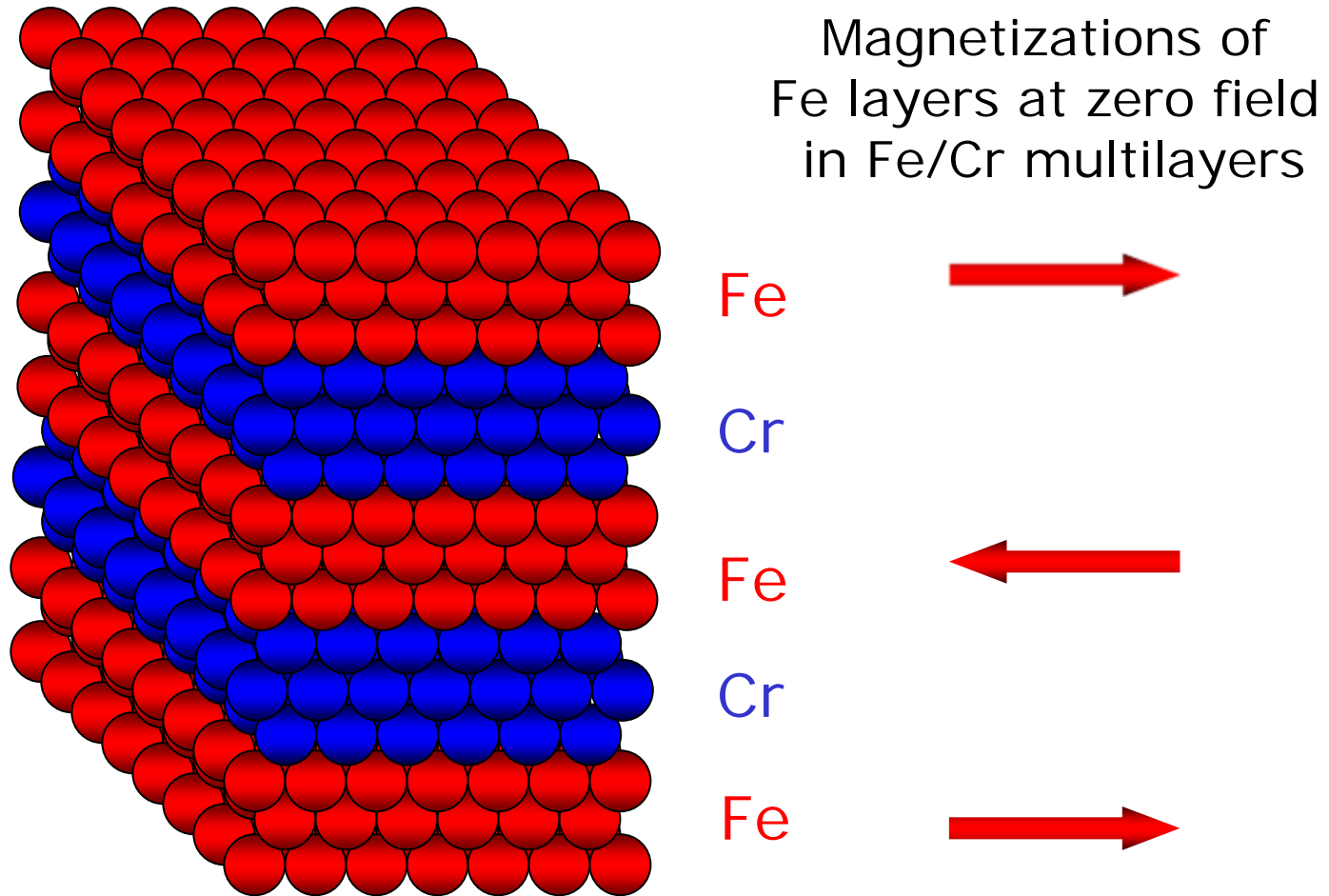
$$\rho_{AB} \approx \rho_A + \rho_B$$



- **Magnetic multilayers**

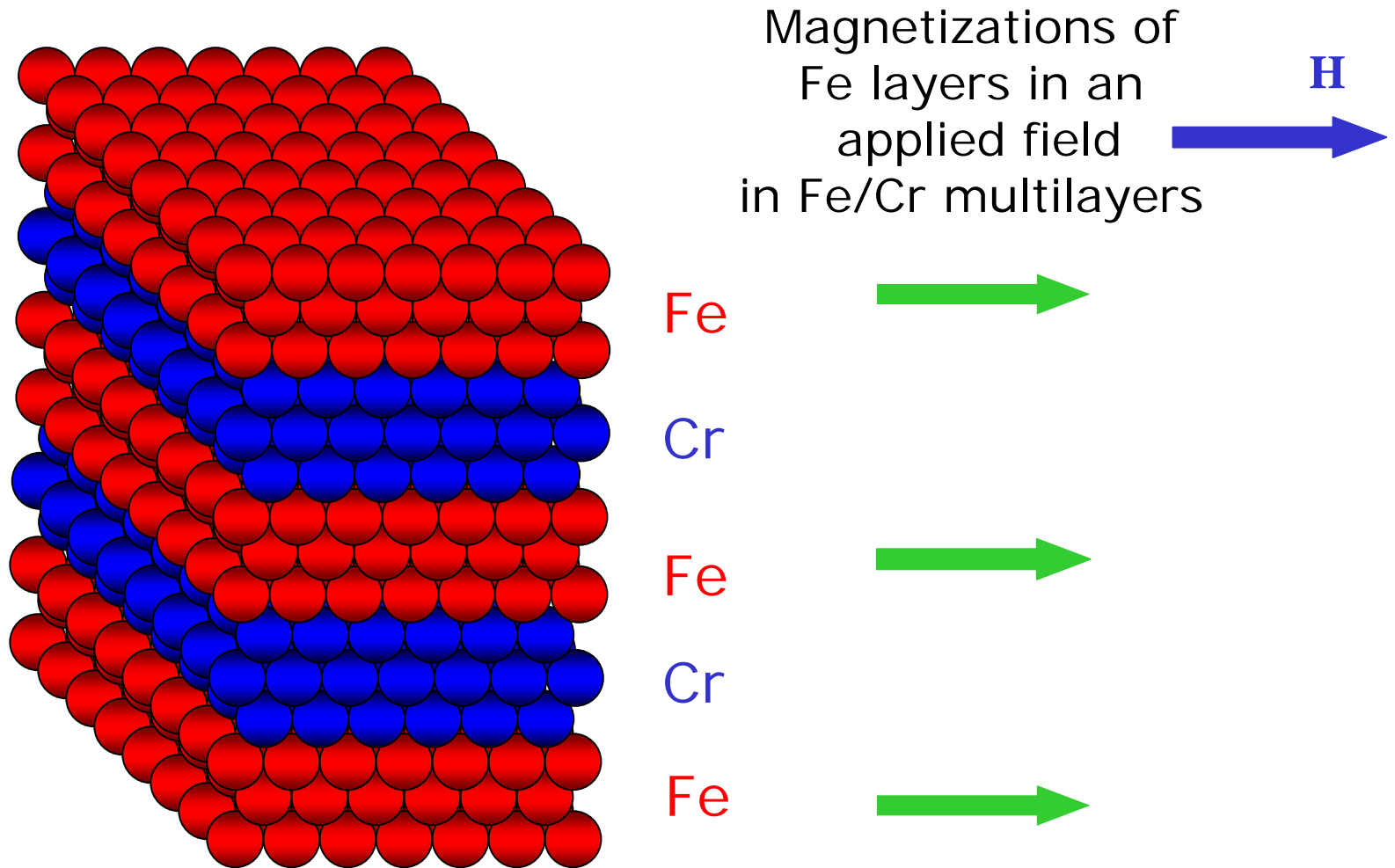


- **Magnetic multilayers**



P. Grünberg, 1986 → antiferromagnetic interlayer coupling

- **Magnetic multilayers**

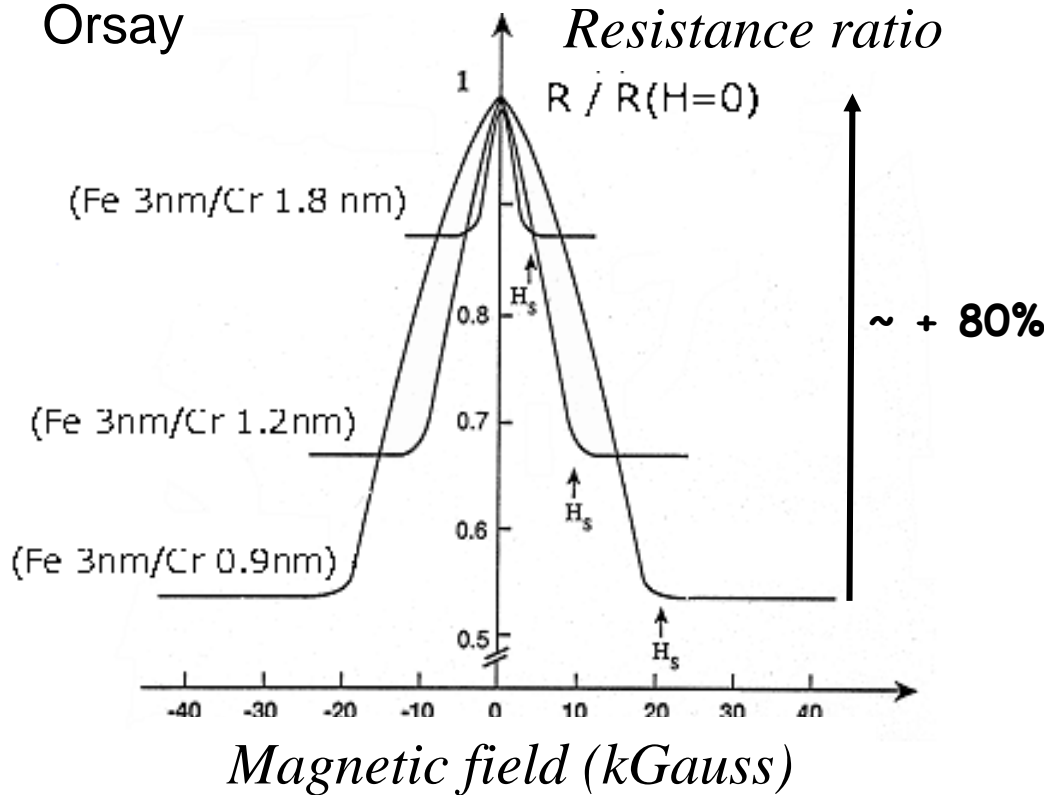


P. Grünberg, 1986 \rightarrow antiferromagnetic interlayer coupling

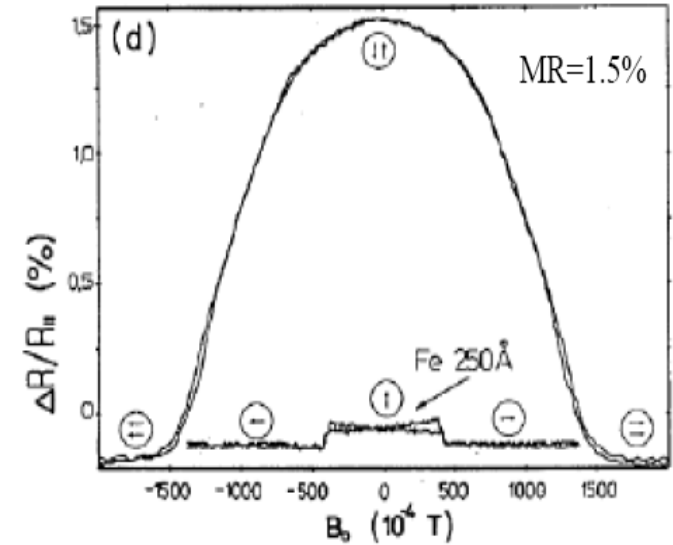
• Giant Magnetoresistance (GMR)

(Orsay, 1988, Fe/Cr multilayers, Jülich, 1989, Fe/Cr/Fe trilayers)

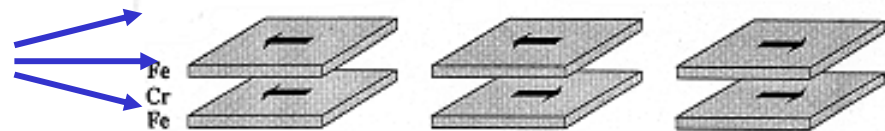
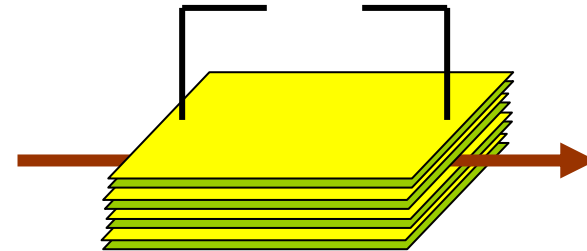
Orsay



Jülich



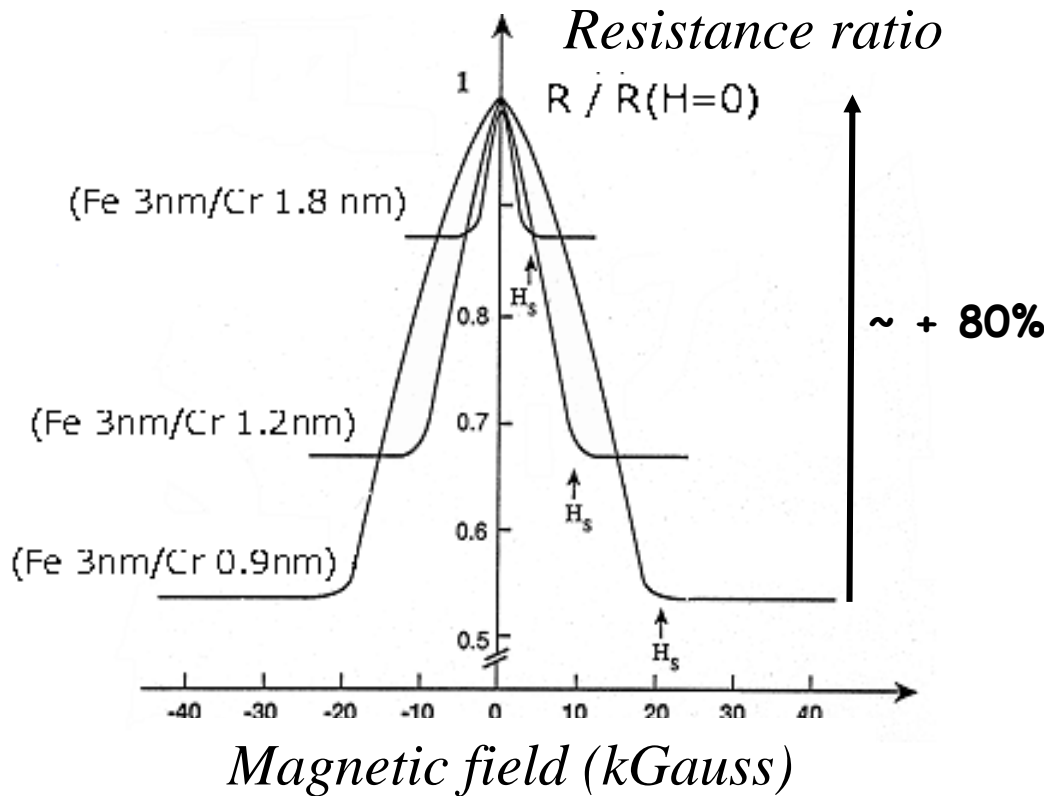
$$V=RI$$



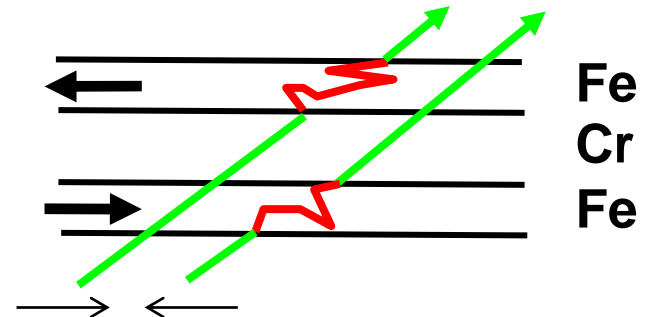
AP (AntiParallel) P (Parallel)

• Giant Magnetoresistance (GMR)

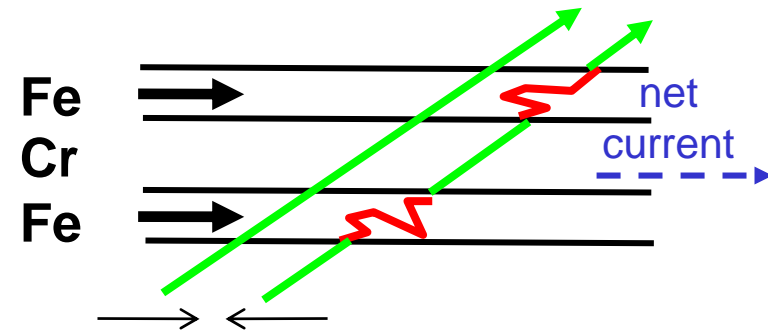
(Orsay, 1988, Fe/Cr multilayers, Jülich, 1989, Fe/Cr/Fe trilayers)



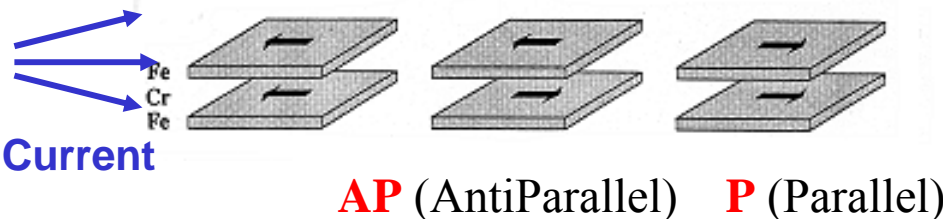
Anti-parallel magnetizations
(zero field, **high** resistance)

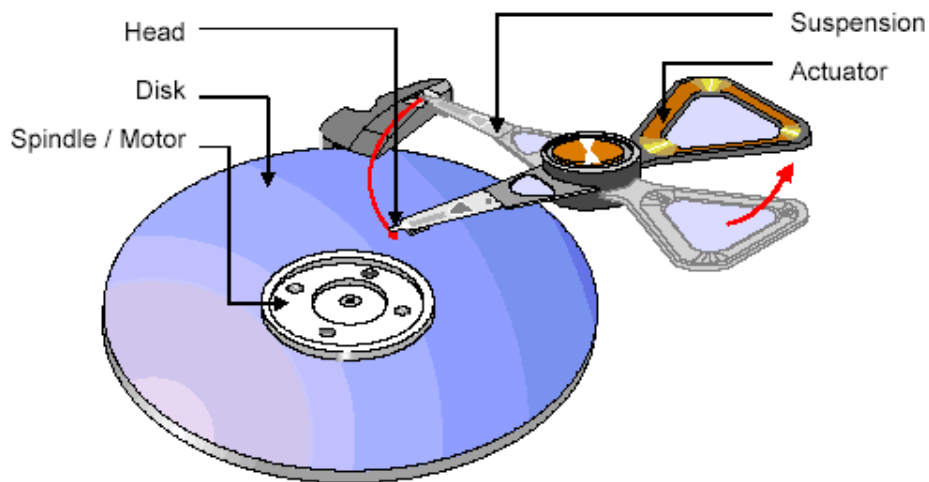


Parallel magnetizations
(appl. field, **low** resist.)



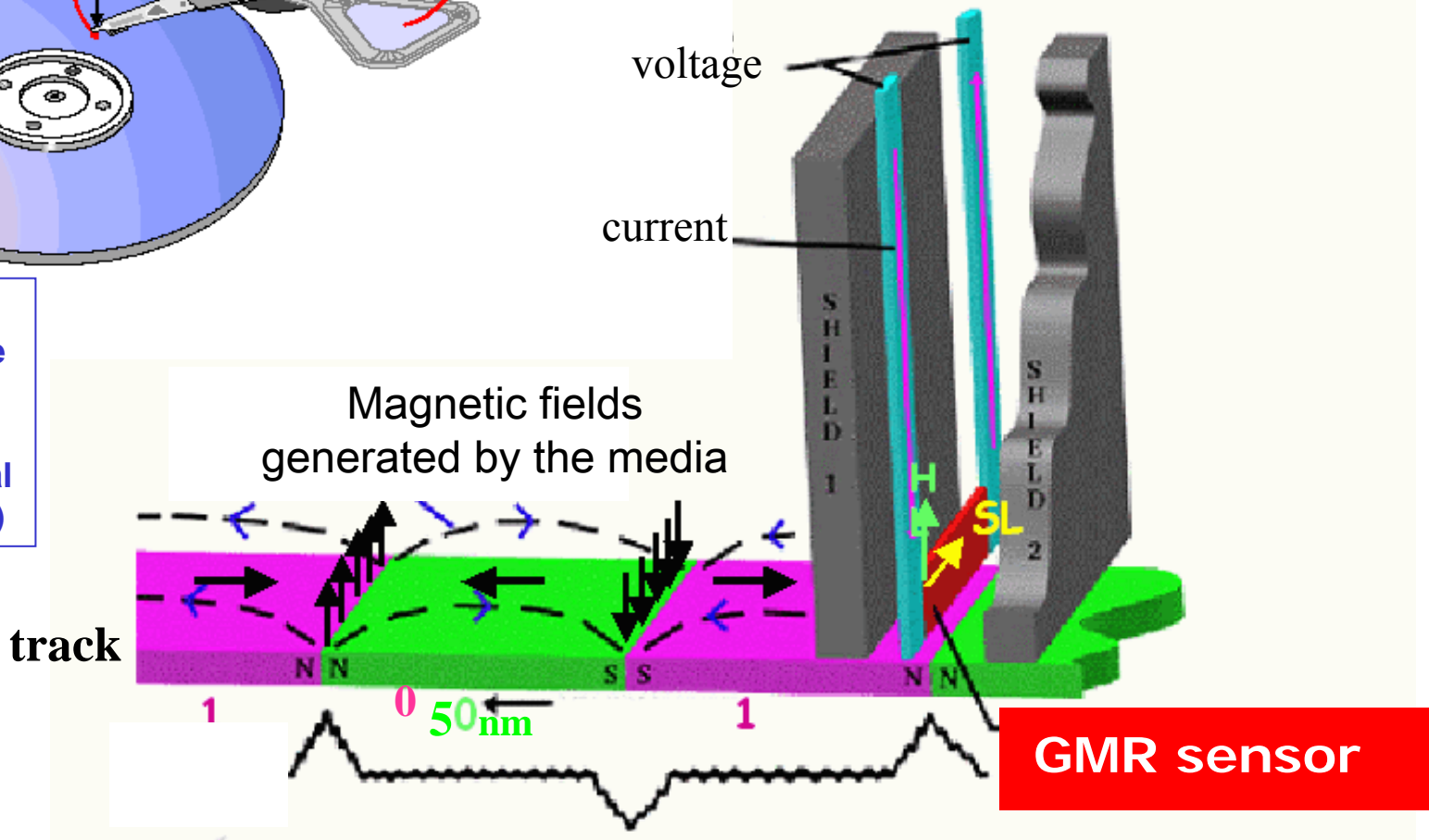
Condition for GMR:
layer thickness \approx nm





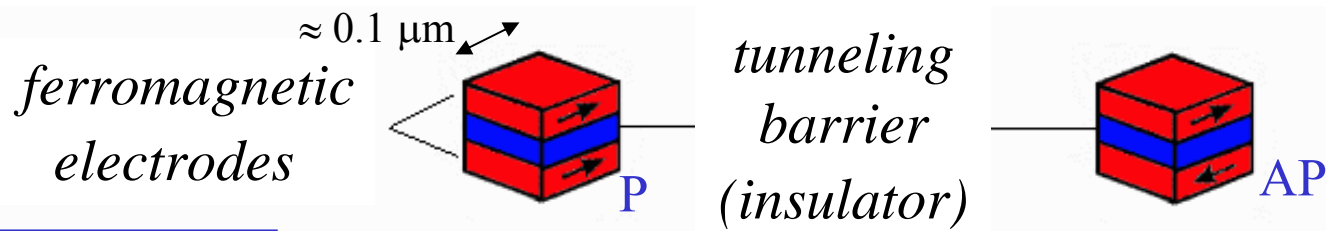
Read head of hard disc drive

Recent review :
« The emergence of spintronics in data storage »
Chappert, AF et al
Nat. Mat.(Nov.07)



1997 (before GMR) : 1 Gbit/in² , 2007 : GMR heads ~ 600 Gbit/in²

Magnetic Tunnel Junctions, Tunneling Magnetoresistance (TMR)



Jullière, 1975, low T, hardly reproducible

Low resistance state

High resistance state

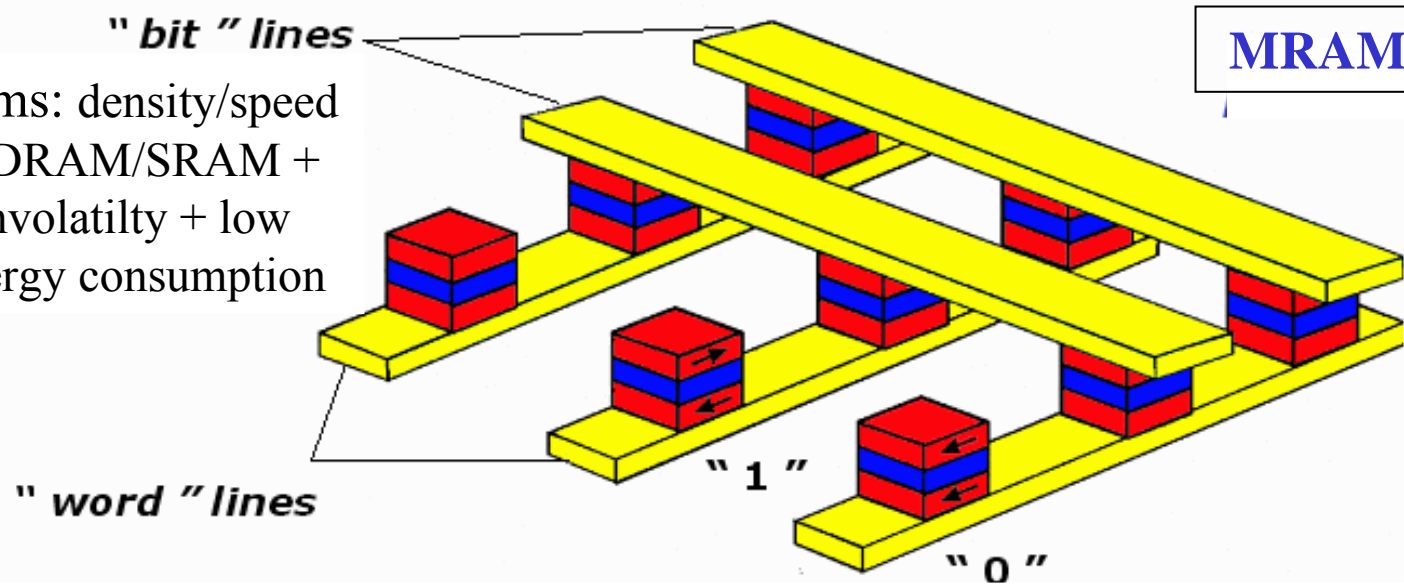
Moodera et al, 1995, Miyasaki et al, 1995, CoFe/Al₂O₃/Co, MR \approx 30-40%

CoFeB/MgO/CoFeB, $\Delta R/R \approx$ 500% at RT in 2006-2007

Applications: - read heads of Hard Disc Drive

- M-RAM (Magnetic Random Access Memory) and STT-RAM

aims: density/speed of DRAM/SRAM + nonvolatility + low energy consumption



MRAM (2006, Freescale)

STT-RAM (in demonstration)
with MgO tunnel junctions
+ writing by spin transfer

Epitaxial magnetic tunnel junctions (MgO, etc)

First examples on Fe/MgO/Fe(001):

CNRS/Thales (Bowen, AF et al, APL2001)

Nancy (Faure-Vincent et al, APL 2003)

Tsukuba (Yuasa et al, Nature Mat. 2005)

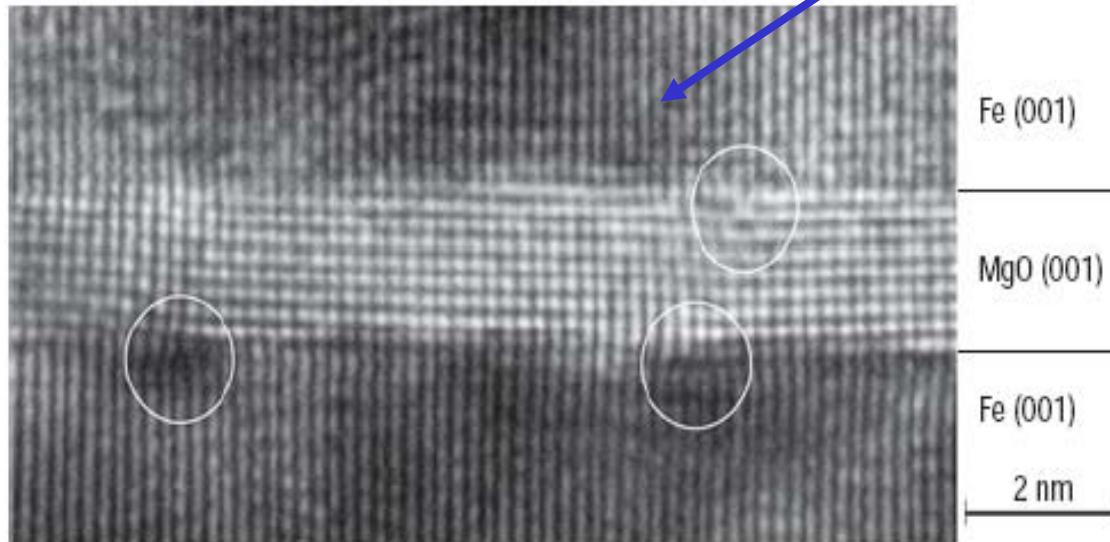
IBM (Parkin et al, Nature Mat. 2005)

....etc

Yuasa et al, Fe/MgO/Fe

Nature Mat. 2005

$$\Delta R/R = (R_{AP} - R_P) / R_P \approx \mathbf{200\%}$$
 at RT



2006-2007

CoFeB/MgO/CoFeB,

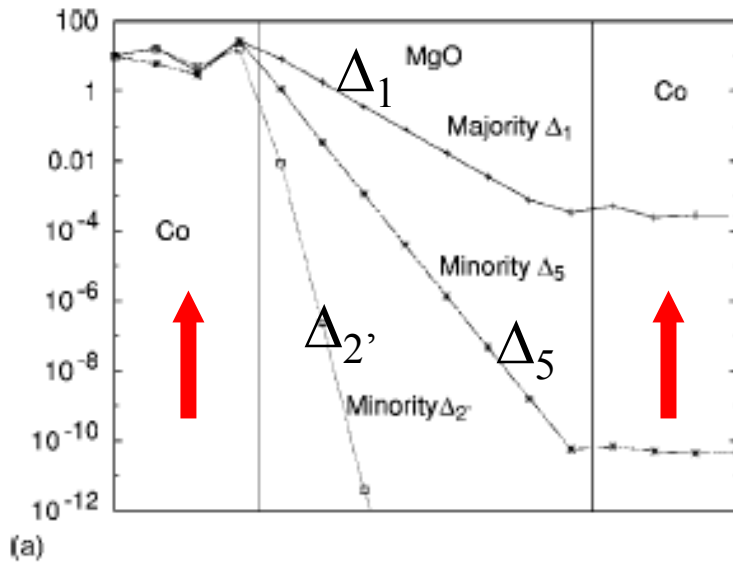
$\Delta R/R \approx \mathbf{500\%}$ at RT in several
laboratories in 2006-2007

+

**Clearer picture of the
physics of TMR:
what is inside the word
« spin polarization »?**

Mathon and Umerski, PR B 1999
Mavropoulos et al, PRL 2000 Butler
et al , PR B 2001
Zhang and Butler, PR B 2004 [bcc
Co/MgO/bcc Co(001)]

P



AP

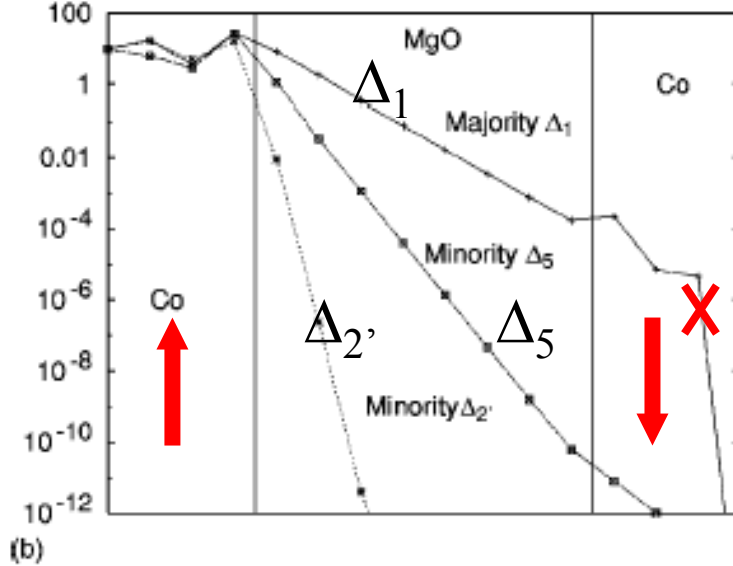
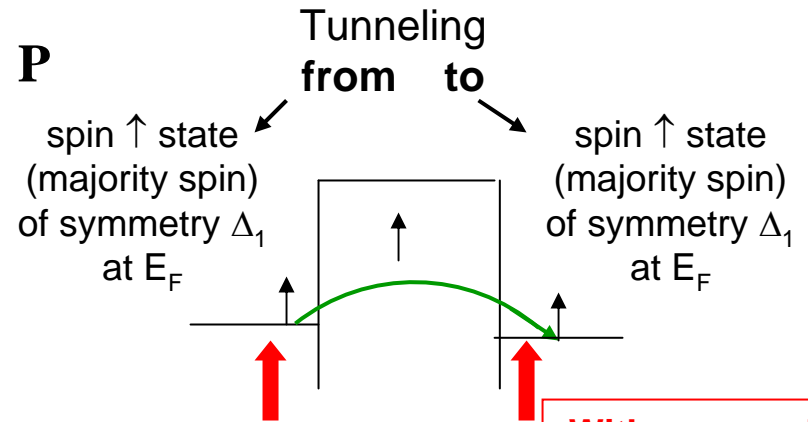
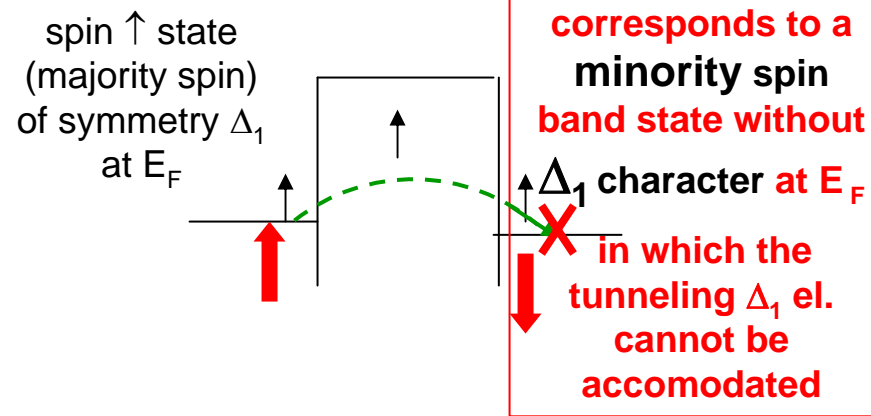


FIG. 2. Tunneling density of states on each atomic layer at $k_{\parallel}=0$ for the Co/MgO/Co tunnel junction. Top panel: parallel spin alignment, bottom panel: antiparallel spin alignment

P



AP



Spin Transfer
(magnetic switching, microwave generation)

Spintronics with semiconductors

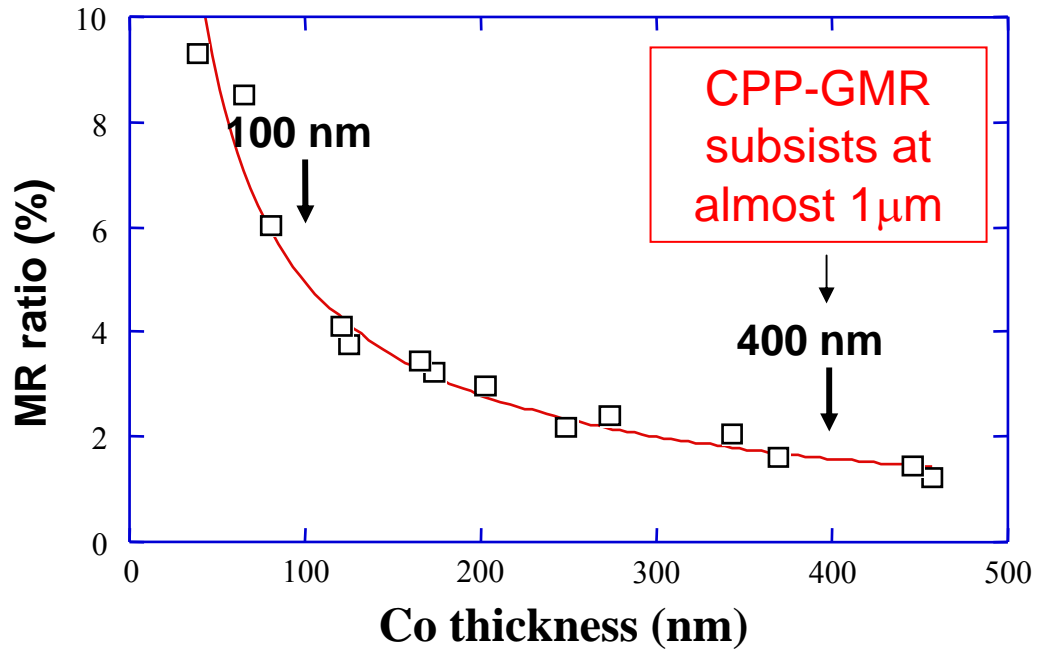
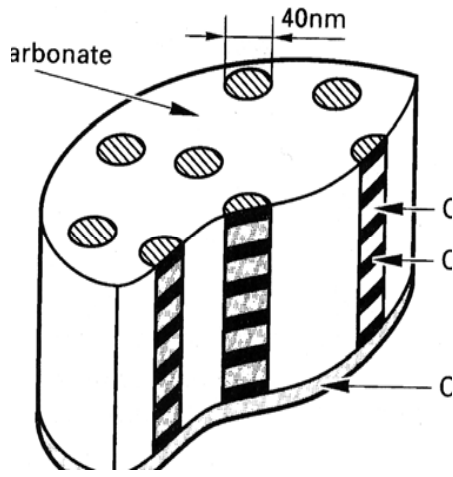
Spintronics with molecules

**Common physics:
spin accumulation**



**spins injected to long distances
by diffusion**

Co/Cu: Current \perp to Plane (CPP) -GMR of multilayered nanowires
 (L.Piraux, AF et al, APL 1994, JMMM 1999)

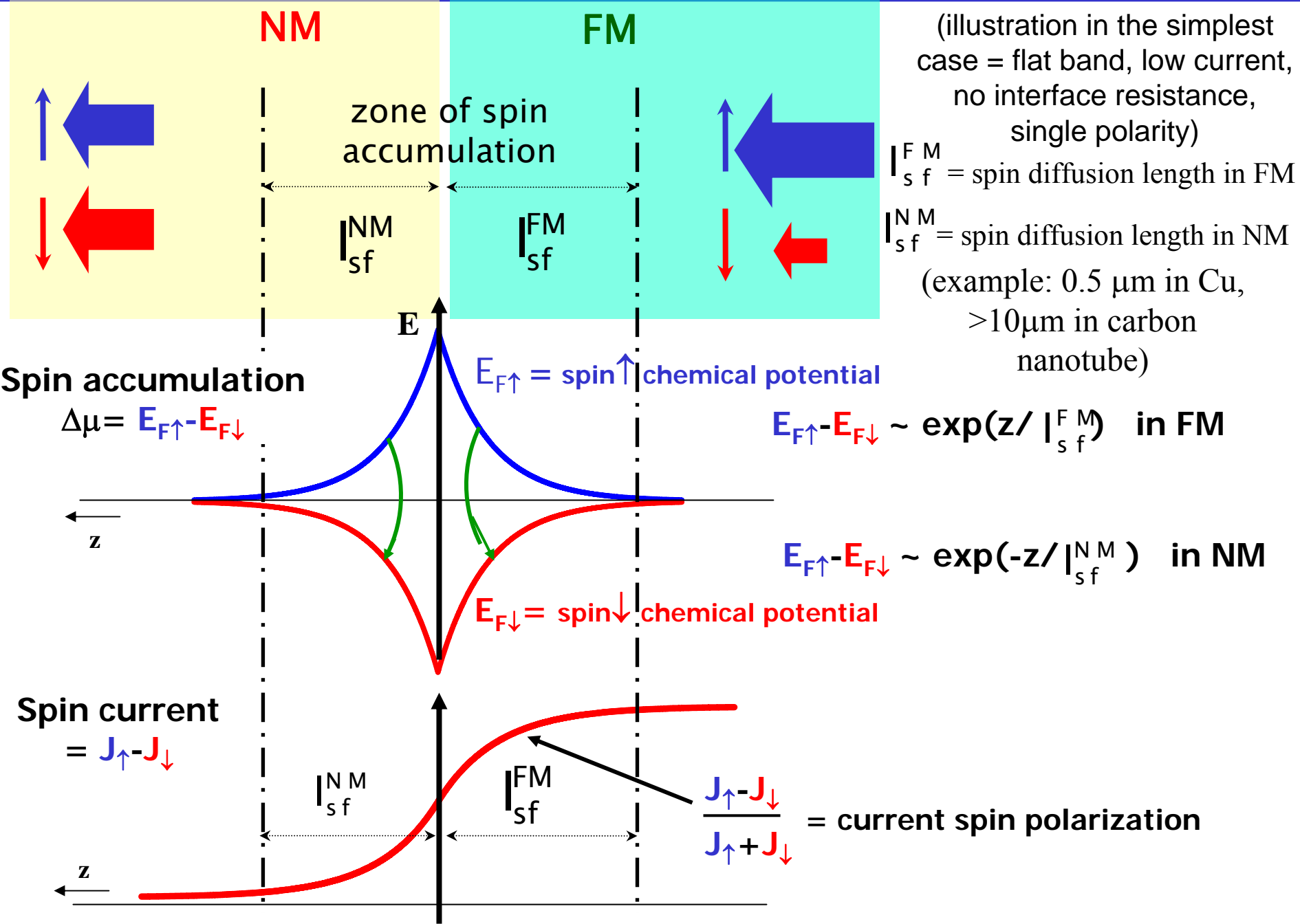


CIP-GMR
 scaling length = mean free path

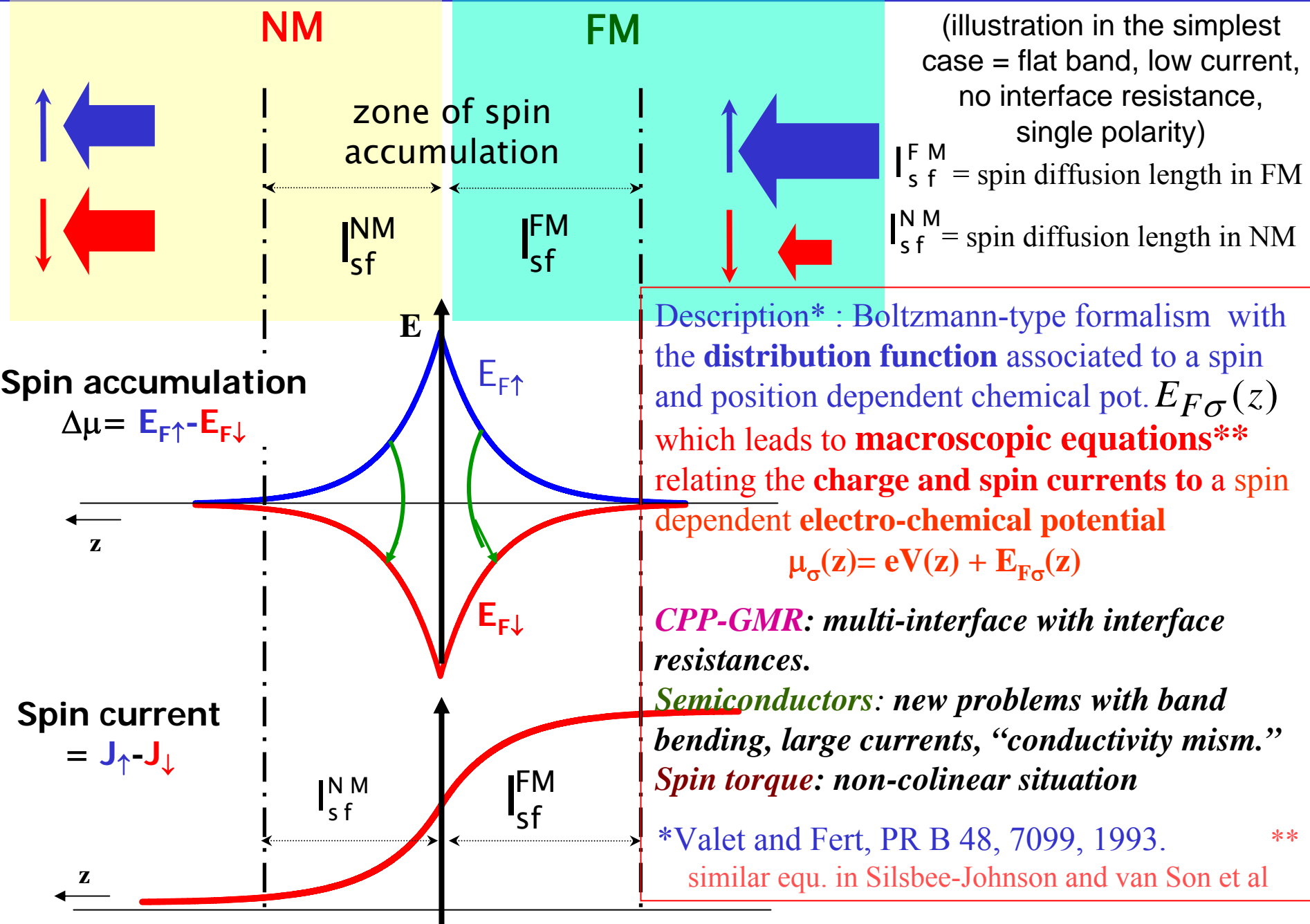
CPP-GMR
 scaling length = spin diffusion length
 \gg mean free path
 spin accumulation theory
 (Valet-Fert, PR B 1993)

Other results: MSU group, PRL 1991, JMMM 1999

Spin injection/extraction at a NM/FM interface (beyond ballistic range)



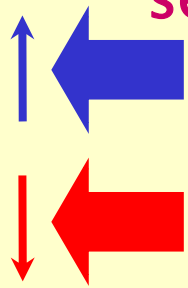
Spin injection/extraction at a NM/FM interface (beyond ballistic range)



Spin injection/extraction at a Semiconductor/FM interface

NM = metal or semiconductor

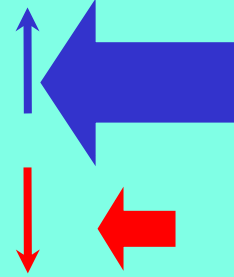
FM



zone of spin accumulation

$|J_{sf}^{NM}|$

$|J_{sf}^{FM}|$



1) situation without interface resistance (« conductivity mismatch »)
(Schmidt et al, PR B 2000)

Semiconductor/ F metal

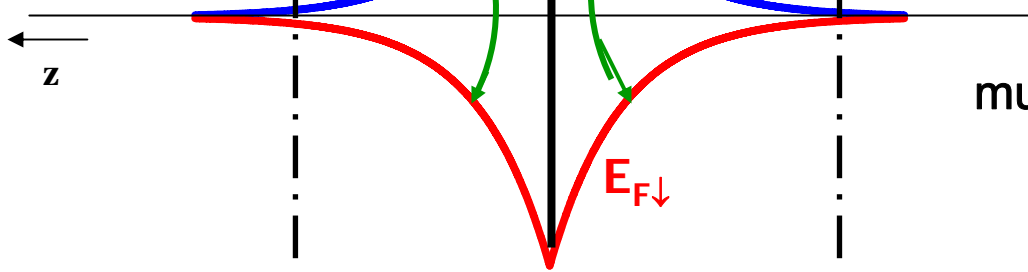
If similar spin splitting on both sides but much larger density of states in F metal

much larger spin accumulation density and much more spin flips on magnetic metal side

almost complete depolarization of the current before it enters the SC

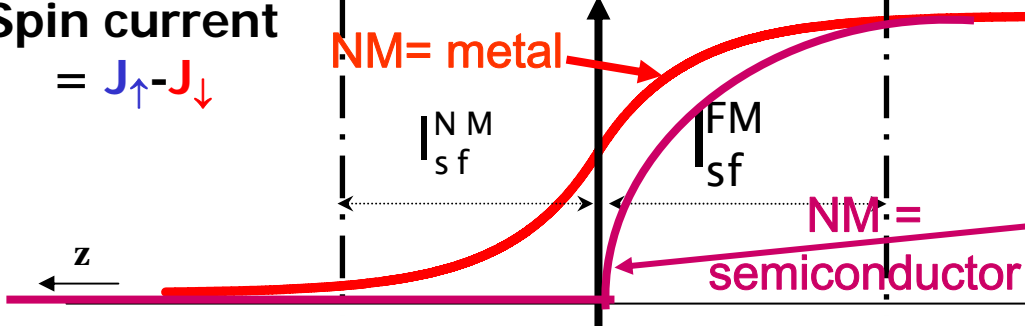
Spin accumulation

$$\Delta\mu = E_{F\uparrow} - E_{F\downarrow}$$



Spin current

$$= J_{\uparrow} - J_{\downarrow}$$



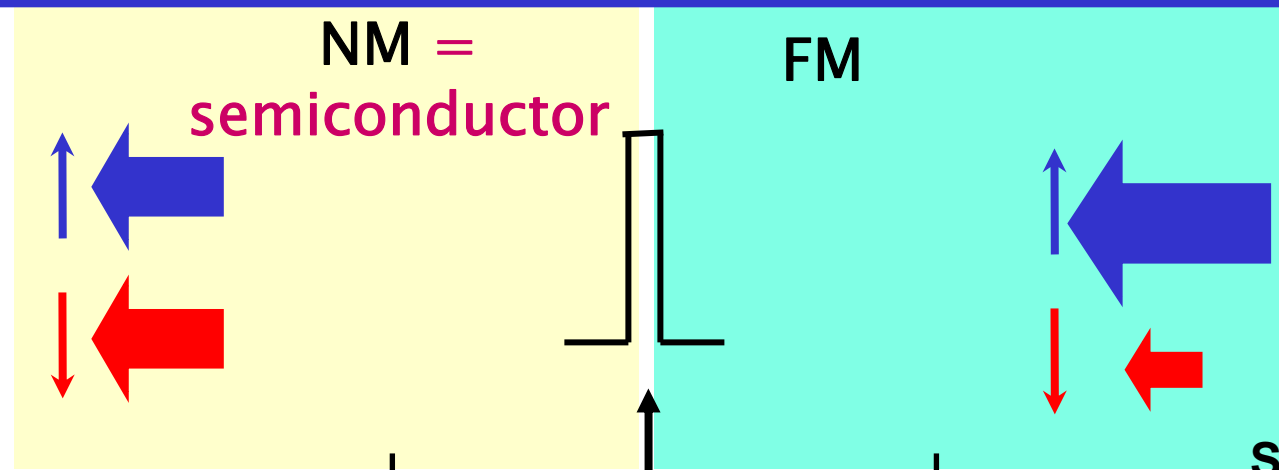
NM = metal

$|J_{sf}^{NM}|$

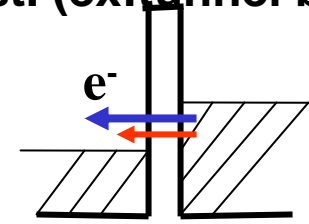
$|J_{sf}^{FM}|$

NM = semiconductor

Spin injection/extraction at a Semiconductor/FM interface



spin dependent. interf. resist. (ex:tunnel barrier)

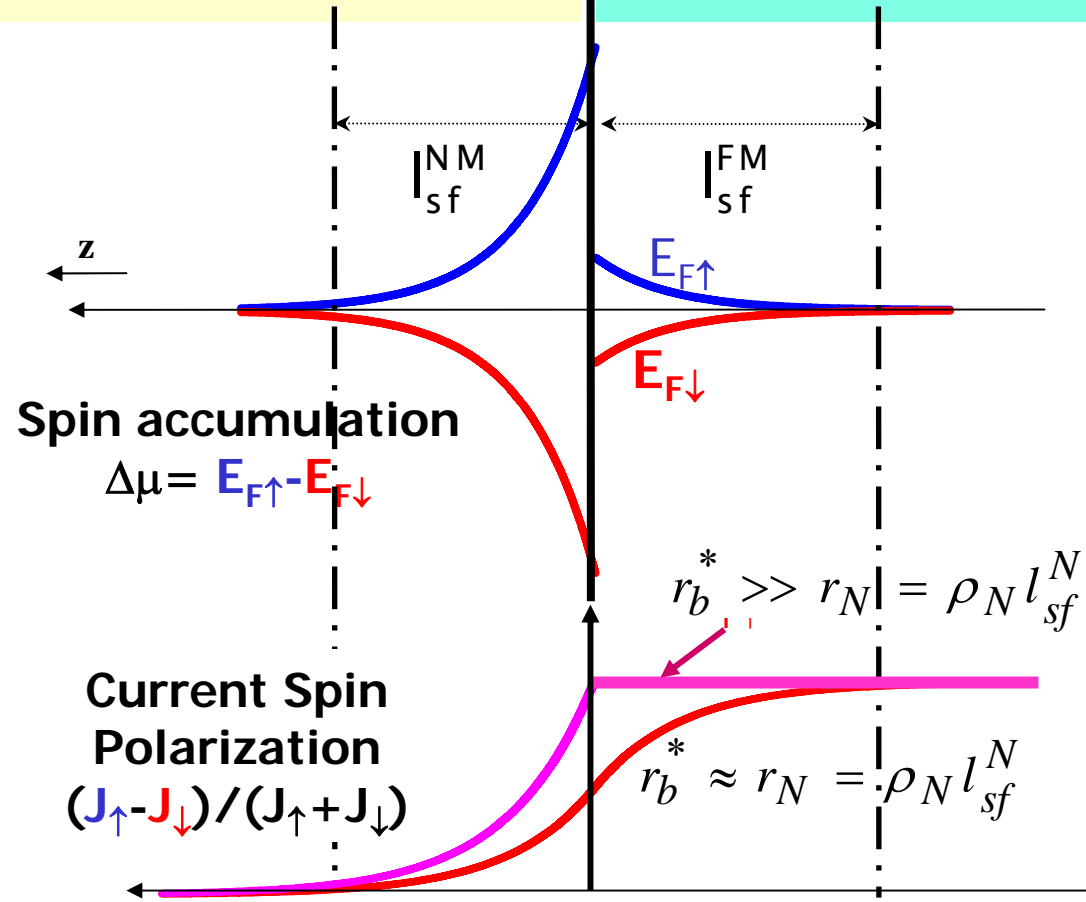


Spin dependent drop of the electro-chemical potential

Discontinuity increases the spin accumulation in NM

re-balanced spin relaxations in F and NM

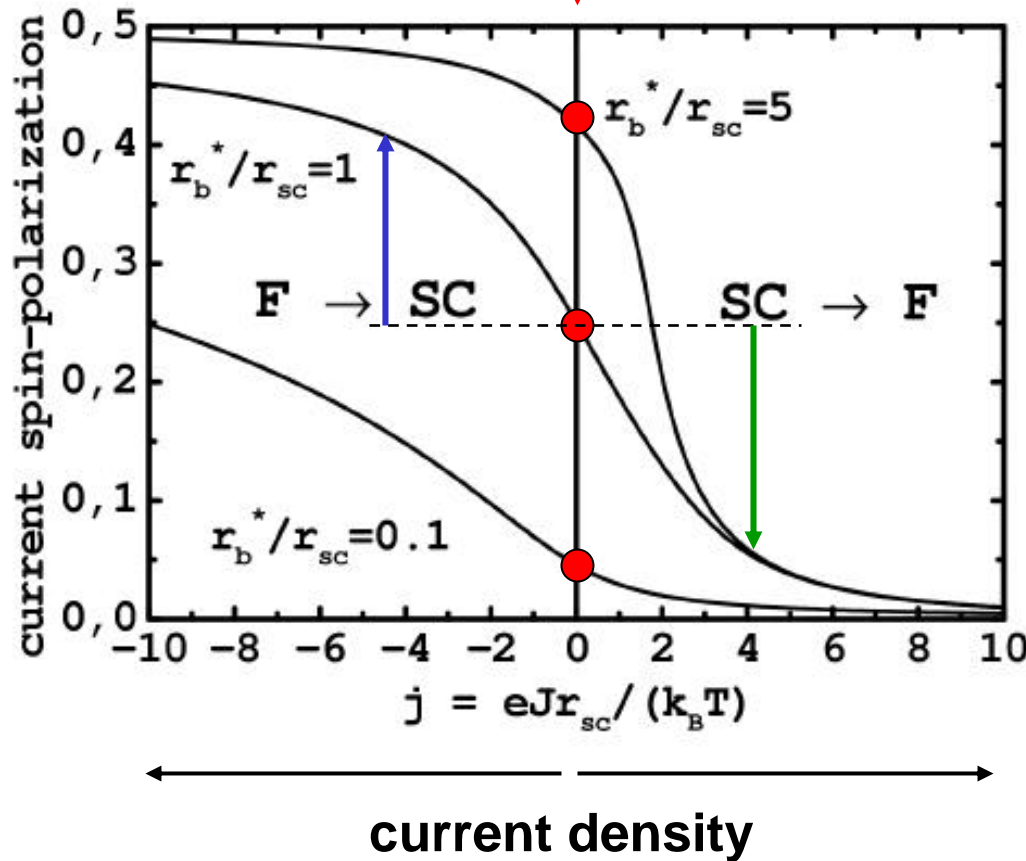
extension of the spin-polarized current into the semiconductor



Rasbah, PR B 2000
A.F-Jaffrès, PR B 2001

Deviations from $\frac{J_{\uparrow} - J_{\downarrow}}{J_{\uparrow} + J_{\downarrow}} = \frac{\beta r_F + \gamma r_b^*}{r_F + r_N + r_b^*}$ at large current density (drift effect)

● = *low current limit*



↑ = deviations from the low current limit (nondegenerate semiconductor)

↓ = deviations from the low current limit (nondegenerate semiconductor)

from Jaffrès and A.F.
(see also Yu and Flatté)

Spin transfer

(transport of magnetization by an electrical current)

- fundamentals

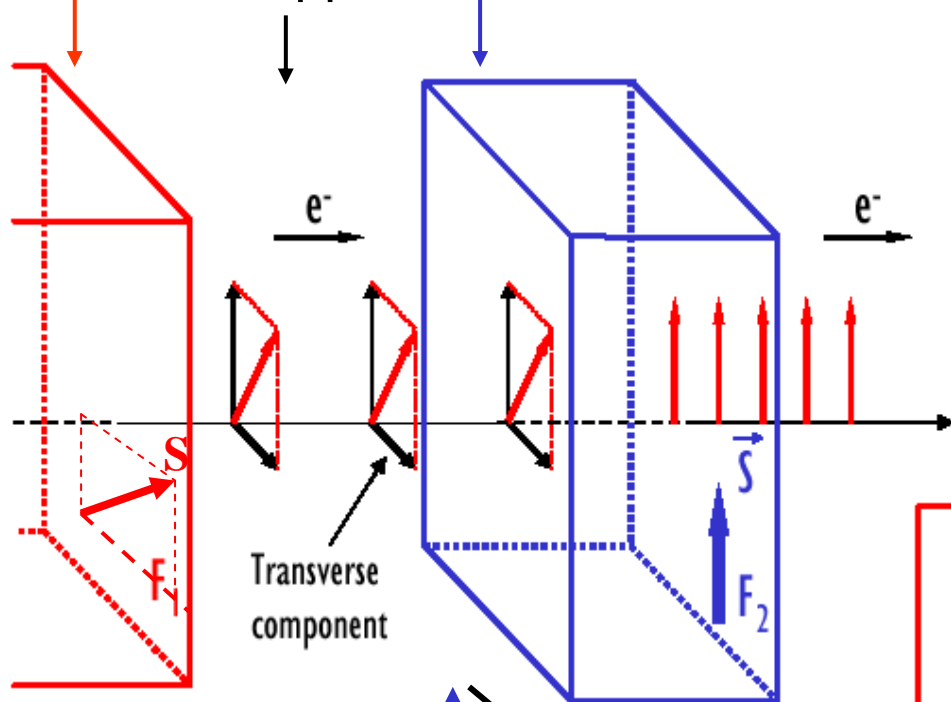
- switching of magnetization by spin transfer and applications (STT-RAM, reprogrammable devices)

- microwave oscillations by spin transfer and applications to telecommunications

Spin transfer

(J. Slonczewski, JMMM 1996, L. Berger, PR B 1996)

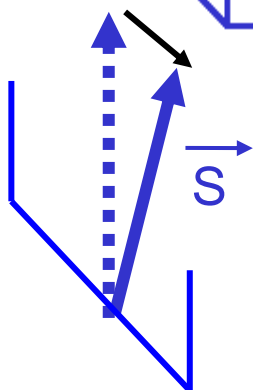
Ex: Cobalt/Copper/ Cobalt



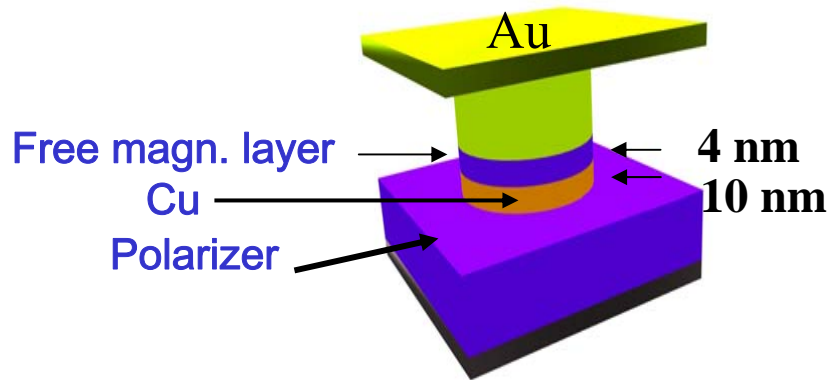
The transverse component of the spin current is absorbed and transferred to the total spin of the layer

$$\frac{\text{torque}}{\hbar} = \left(\frac{d\vec{S}}{dt} \right)_i = \text{absorbed transverse spin current} \propto j \mathbf{M} \times (\mathbf{M} \times \mathbf{M}_0)$$

\equiv Torque on \mathbf{S}
 $\approx \mathbf{M} \times (\mathbf{M} \times \mathbf{M}_0)$

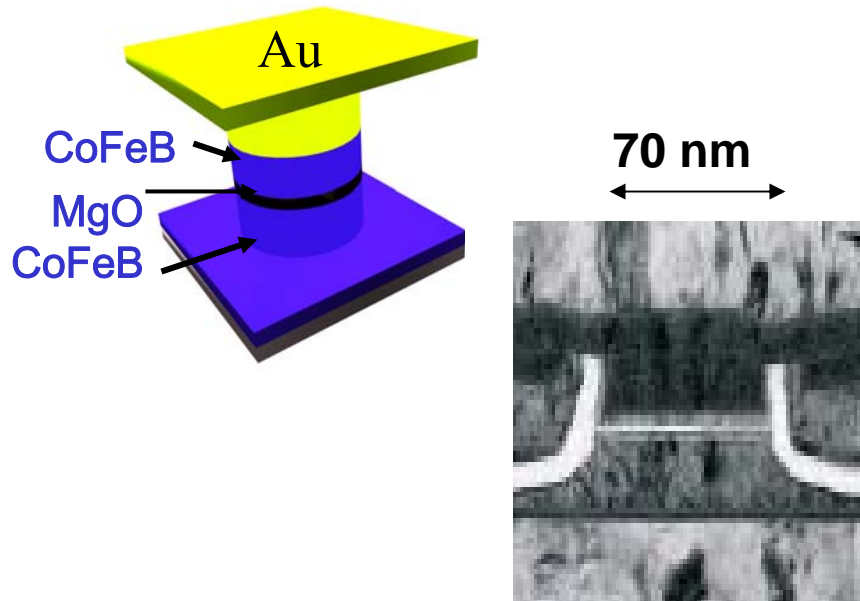


Trilayered pillar or tunnel junction

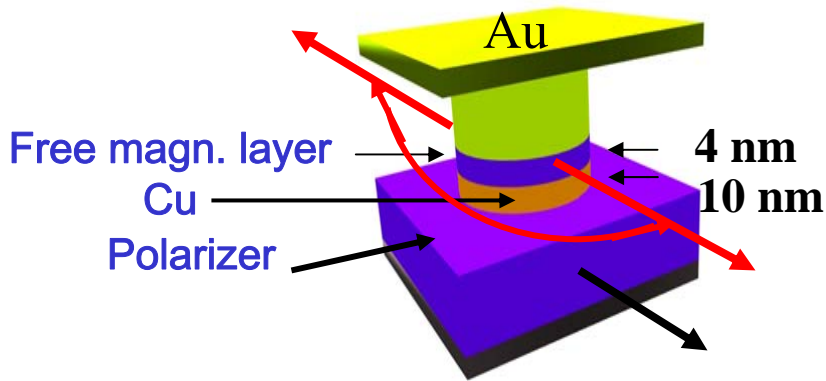


Metallic pillar $\approx 50 \times 150 \text{ nm}^2$

Tunnel junction $\approx 50 \times 170 \text{ nm}^2$

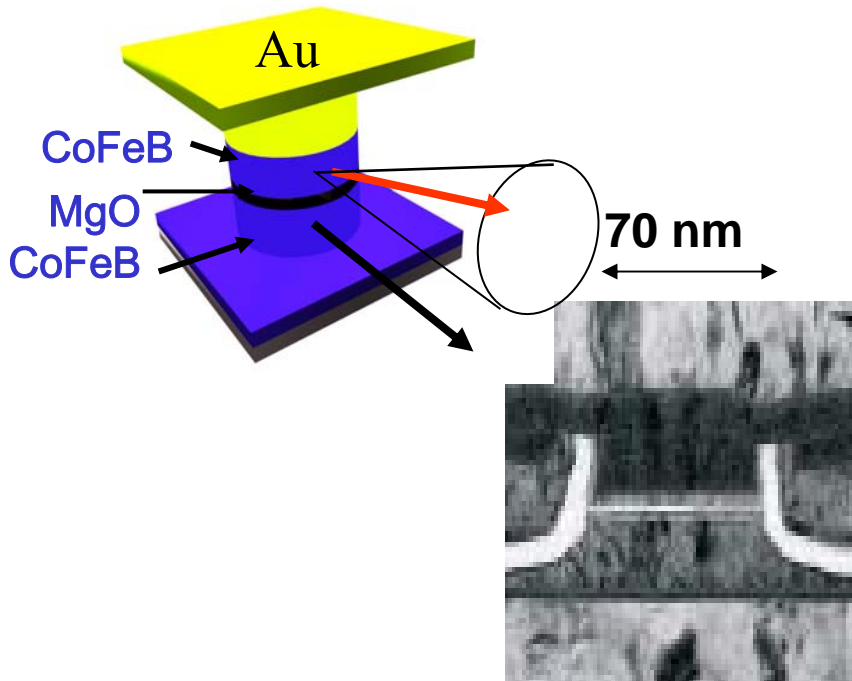


Trilayered pillar or tunnel junction



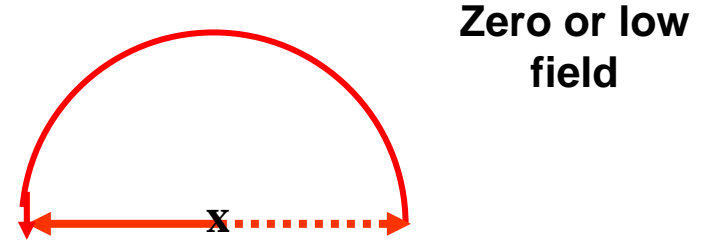
Metallic pillar $\approx 50 \times 150 \text{ nm}^2$

Tunnel junction $\approx 50 \times 170 \text{ nm}^2$



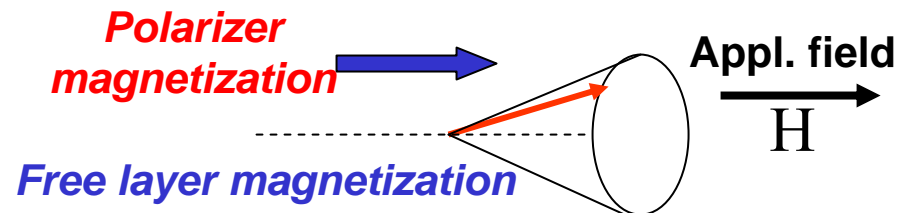
Two regimes of spin transfer

1) Magnetization switching by spin transfer



Applications: writing a memory, etc

2) Sustained precession of the magnetization of the free layer and generation of radio-frequency oscillations



Applications: spin transfer nano-oscillators (NSTOs) for communications (telephone, radio, radar)

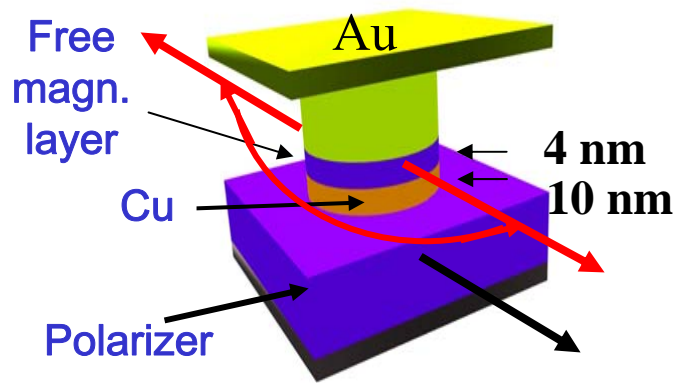
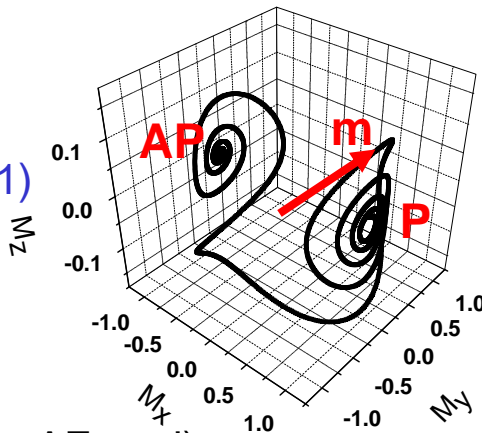
Regime of irreversible magnetic switching

First experiments on pillars:

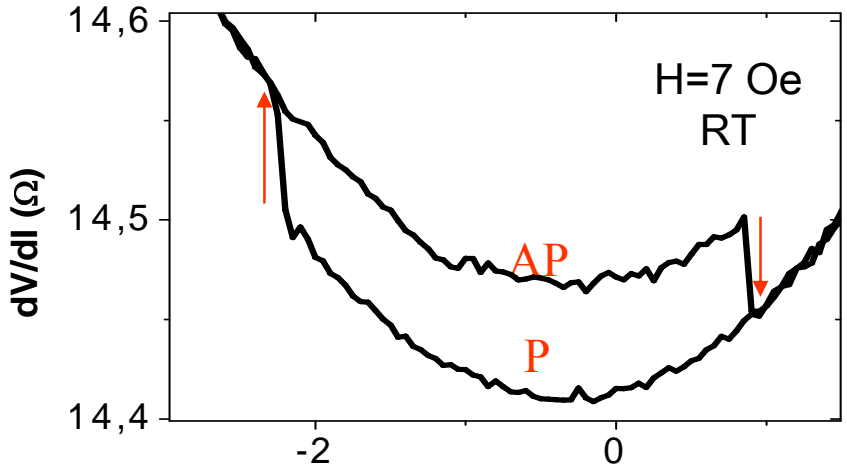
Cornell (Katine et al, PRL 2000)

CNRS/Thales (Grollier et al, APL 2001)

IBM (Sun et al, APL 2002)



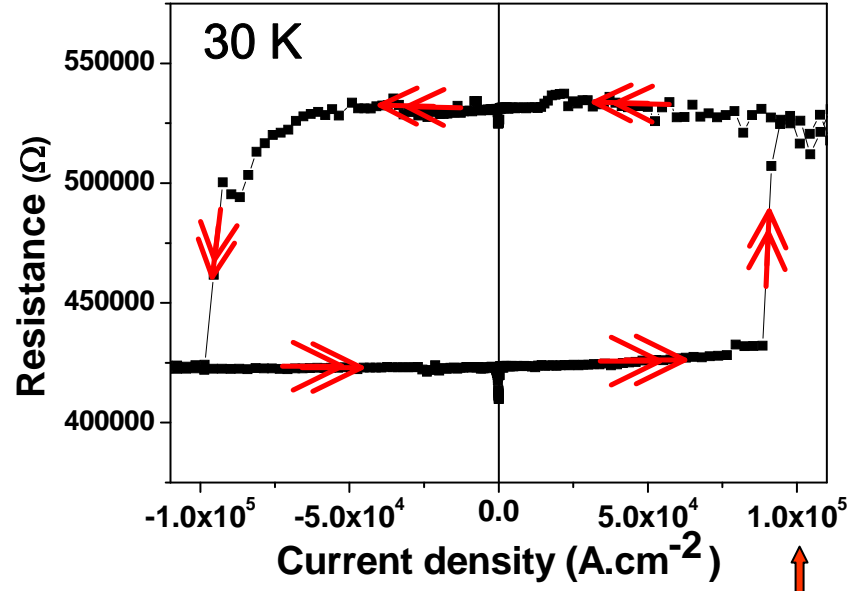
Py/Cu/Py 50nmX150nm (Boulle, AF et al)



Py = permalloy

I (mA)

GaMnAs/InGaAs/GaMnAs tunnel junction (MR=150%) (Elsen, AF et al, PR B 2006)

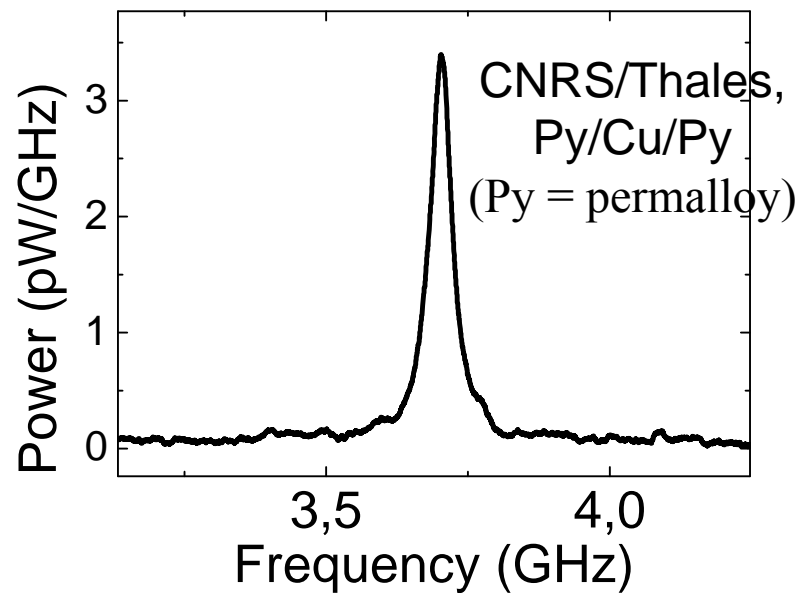
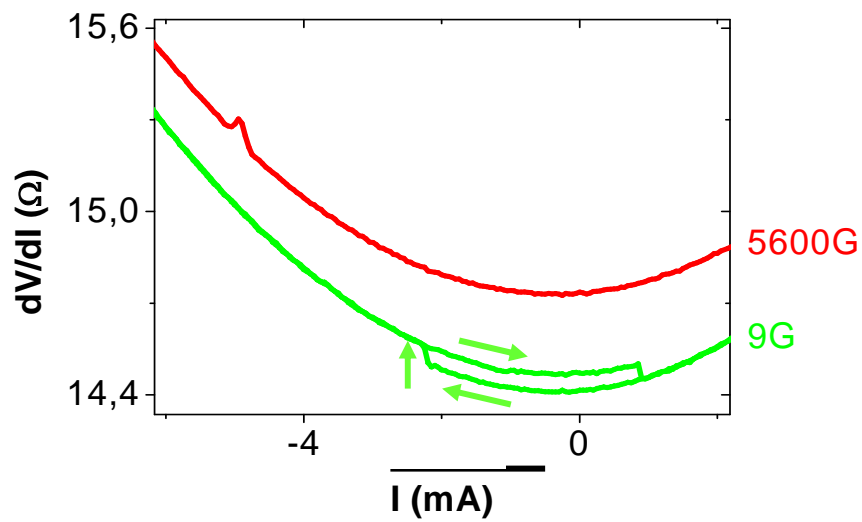
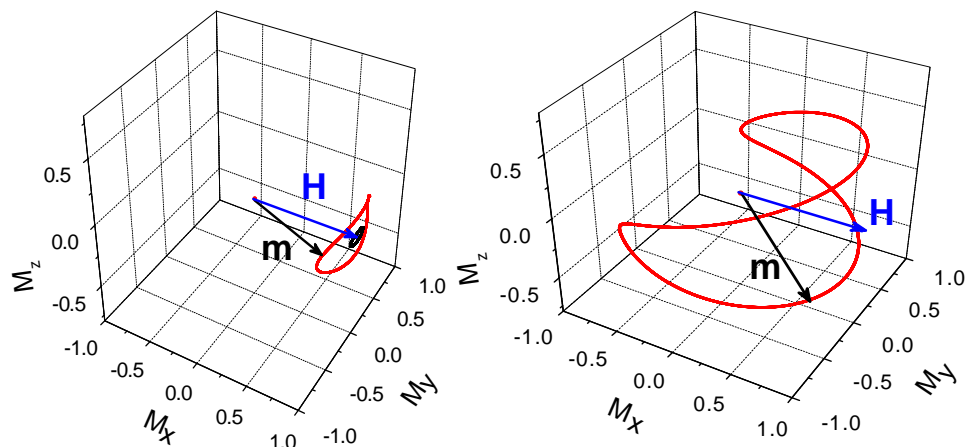
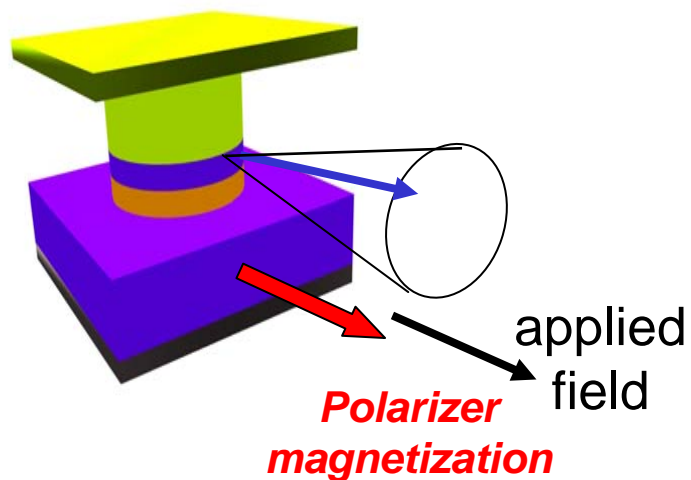


$1 \times 10^5 \text{ A/cm}^2$

typical switching current $\approx 10^7 \text{ A/cm}^2$

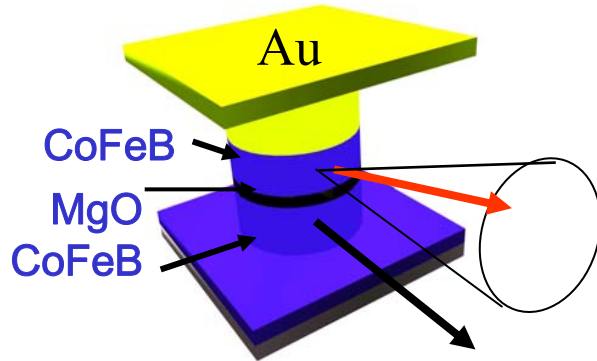
switching time can be as short as 0.1 ns (Chappert et al)

Regime of steady precession (microwave frequency range)



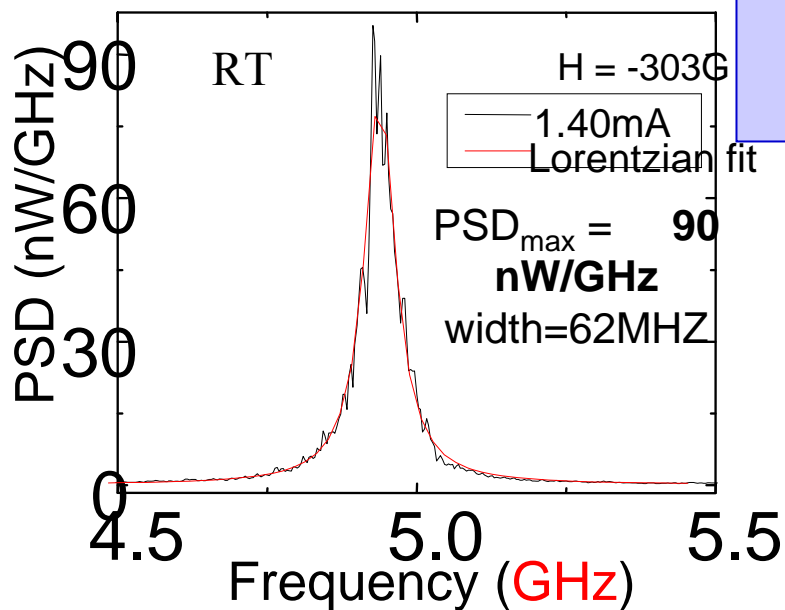
Microwave power spectrum of the oscillations of a permalloy-based pillar

Tunnel junction $\approx 50 \times 170 \text{ nm}^2$



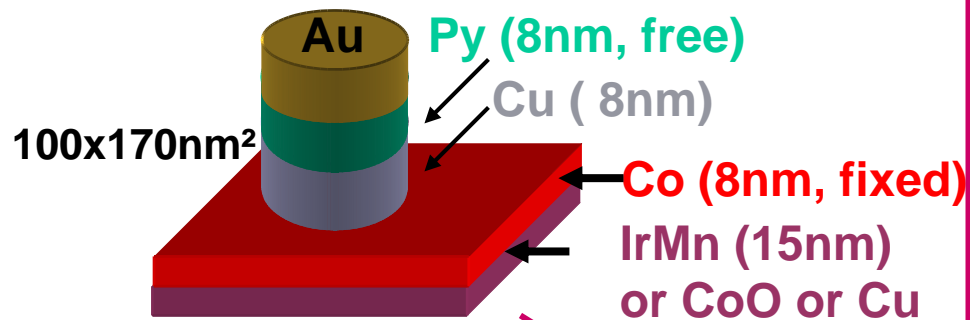
Spin Transfer mixes very different (and interacting) problems:

- transport (in metallic pillars, tunnel junctions, point contacts)**
- problems of non-linear dynamics**
- micromagnetism (non-uniform excitations, vortex motion..)**



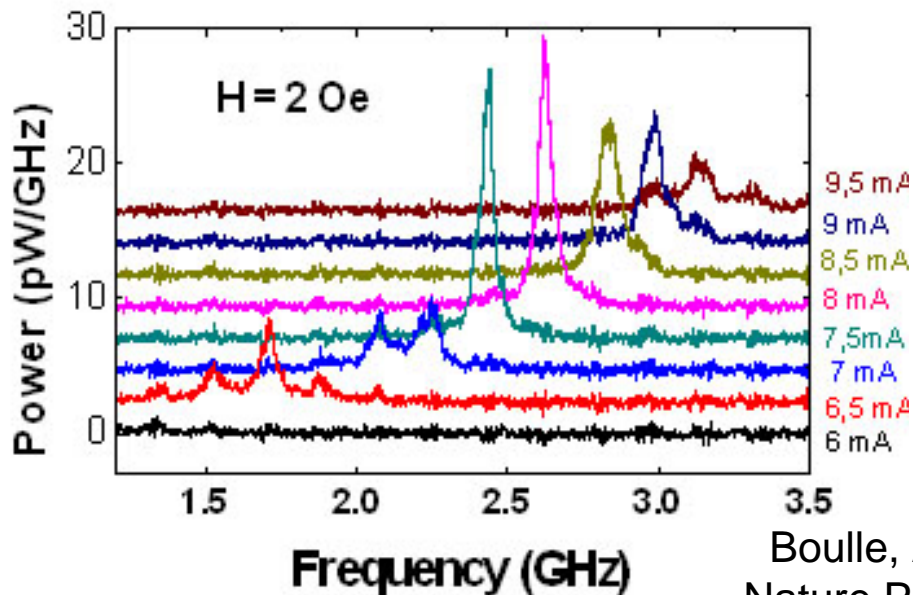
CoFeB/MgO/CoFeB junction (J.Grollier, AF et al 2008, collaboration S. Yuasa et al, AIST)

Co/Cu/Py (« wavy » angular variation
calculated by Barnas, AF et al, PR B 2005)

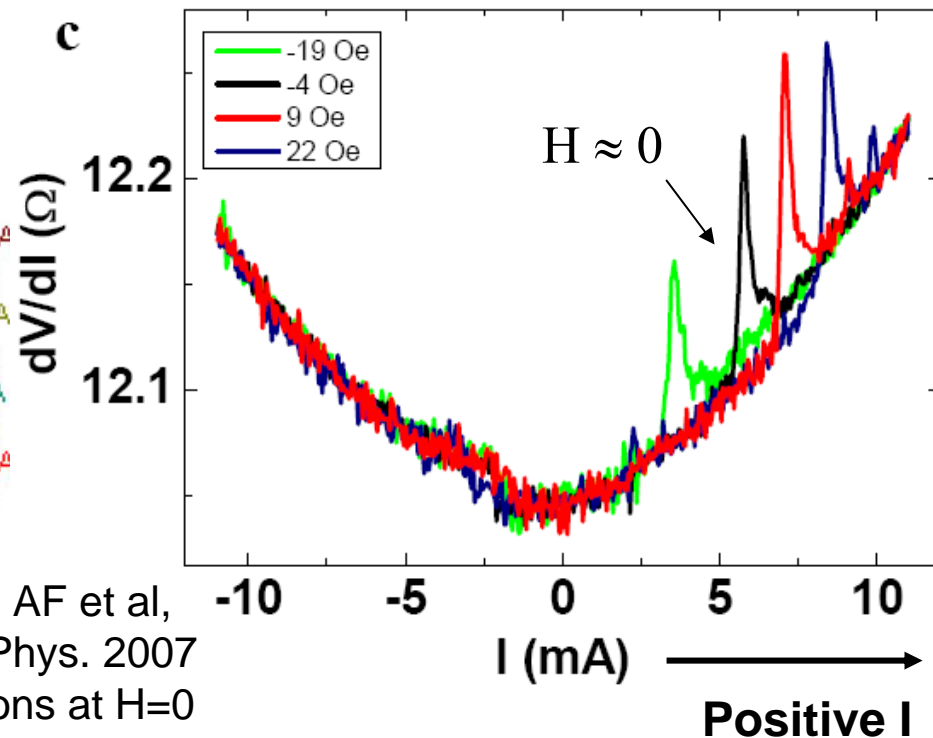
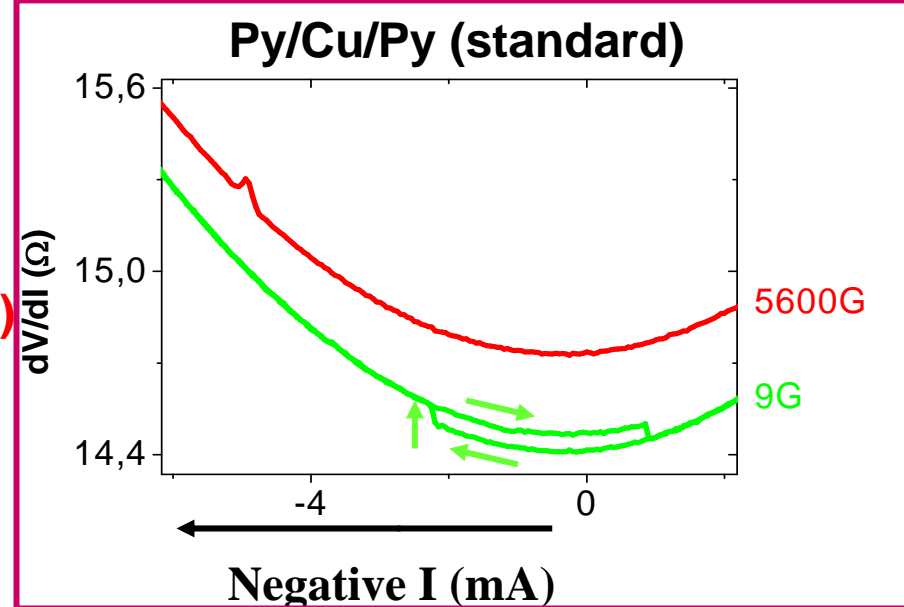


free Py:fast spin
relaxation

fixed Co: slower spin
relaxation



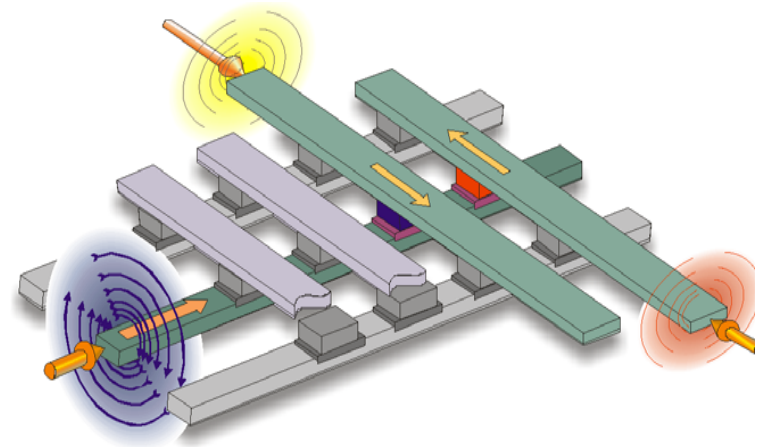
Bouille, AF et al,
Nature Phys. 2007
oscillations at H=0



Applications of magnetic switching by spin transfer

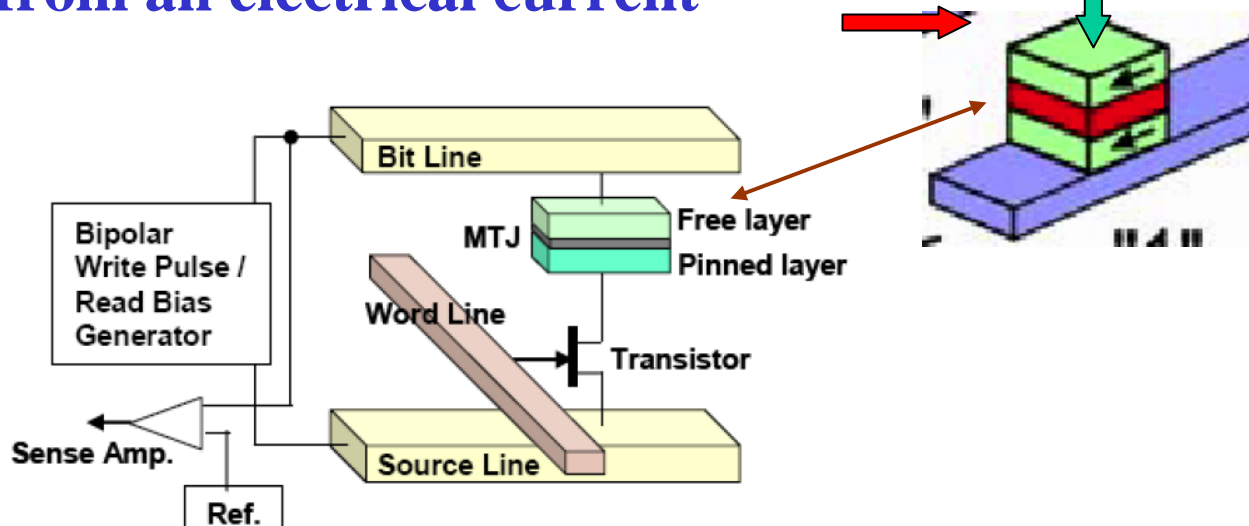
Switching of reprogrammable devices (example: STT-RAM)

To replace M-RAM (switching by external magnetic field : *nonlocal*, risk of « cross-talk » limiting integration, too large currents)



STT-RAM : «Electronic» reversal by spin transfer from an electrical current

Current pulse

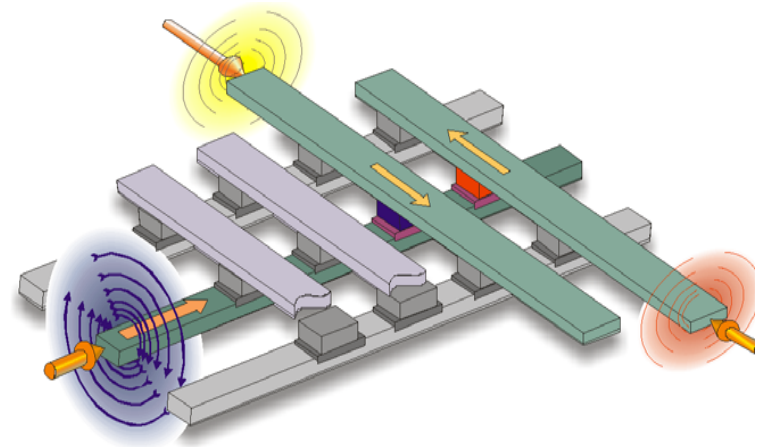


Source : SpinRAM SONY, IEEE 2005

Applications of magnetic switching by spin transfer

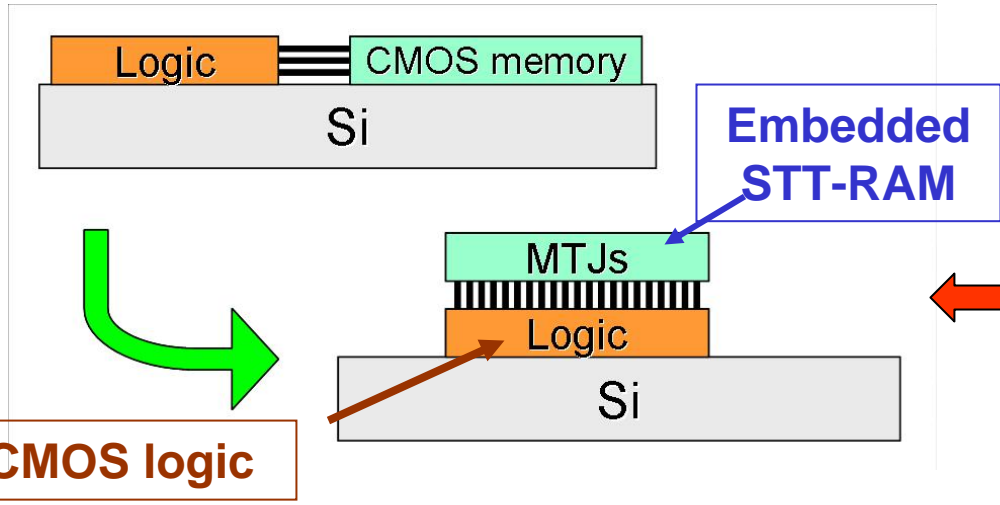
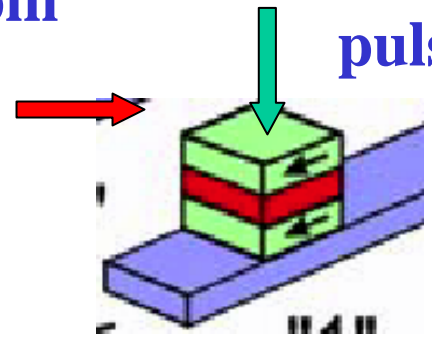
Switching of reprogrammable devices (example: STT-RAM)

To replace M-RAM (switching by external magnetic field : *nonlocal*, risk of « cross-talk » limiting integration, too large currents)



STT-RAM : «Electronic» reversal by spin transfer from an electrical current

Current pulse

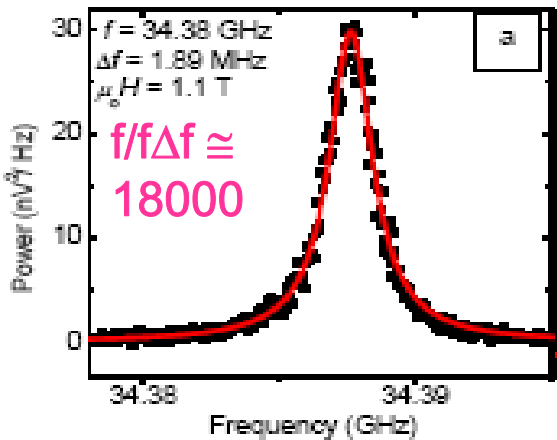


Non volatile FPGA Logic Circuits

Flash and SRAM would be replaced by a non volatile memory (<math><10F^2</math>) embedded directly inside the look up table (Sony, IEEE Proc. 07)

Spin Transfer Oscillators (STOs)

(telecommunications, radar, chip to chip communication...)



Advantages:

- direct oscillation in the microwave range (0.5-40 GHz)
- agility: control of frequency by dc current amplitude
- high quality factor
- small size ($\approx 0.1\mu\text{m}$) (on-chip integration, chip to chip com., microwave assisted writing in HDD)

-Needed improvements

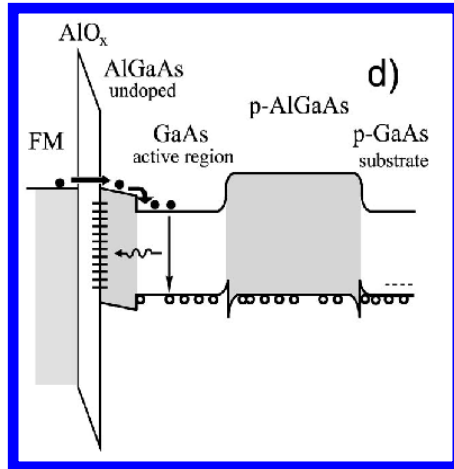
- Increase of power by synchronization of a large number N of STOs ($\times N^2$)
- Optimization of the emission linewidth

Spintronics with semiconductors and molecules

Spintronics with semiconductors

Magnetic metal/semiconductor hybrid structures

Example: spin injection from Fe into LED (Mostnyi et al, PR. B 68, 2003)



Ferromagnetic semiconductors (FS)

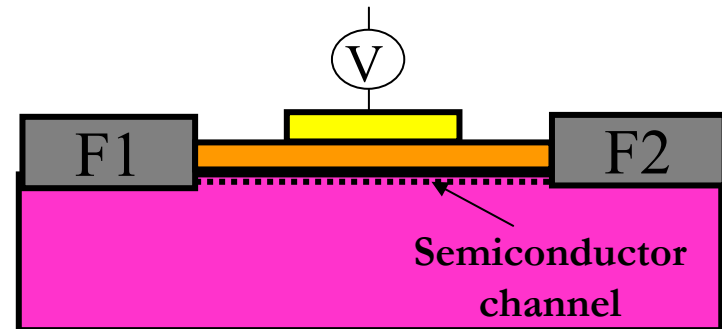
GaMnAs ($T_c \rightarrow 170\text{K}$) and R.T. FS

Electrical control of ferromagnetism

TMR, TAMR, spin transfer (GaMnAs)

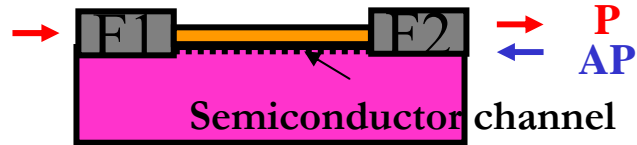
Field-induced metal/insulator transition

Logic devices, spin transistor ?



Semiconductor lateral channel between spin-polarized source and drain transforming spin information into large(?) and tunable (by gate voltage) electrical signal

Nonmagnetic lateral channel between spin-polarized source and drain



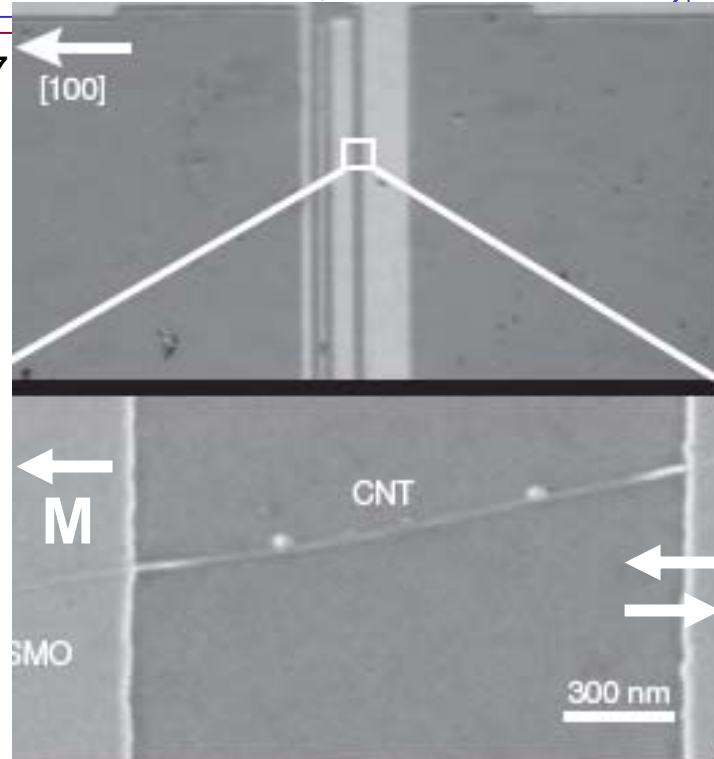
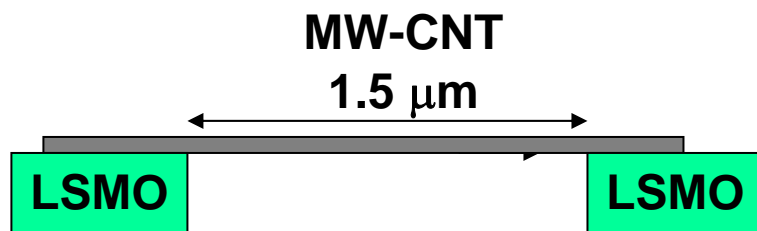
Semiconductor channel:

« Measured effects of the order of **0.1-1%** have been reported for the change in voltage or resistance (between **P** and **AP**).... », from the review article « *Electrical Spin Injection and Transport in Semiconductors* » by **BT Jonker** and **ME Flatté** in *Nanomagnetism* (ed.: **DL Mills** and **JAC Bland**, Elsevier 2006)

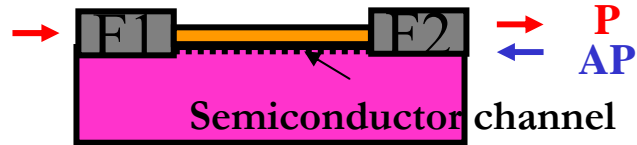
L.Hueso, N.D. Mathur, A.F. et al, Nature 445, 410, 2007

Carbon nanotubes:

$$\Delta R/R \approx 60-70\%, V_{AP}-V_P \approx 20-60 \text{ mV}$$



Nonmagnetic lateral channel between spin-polarized source and drain



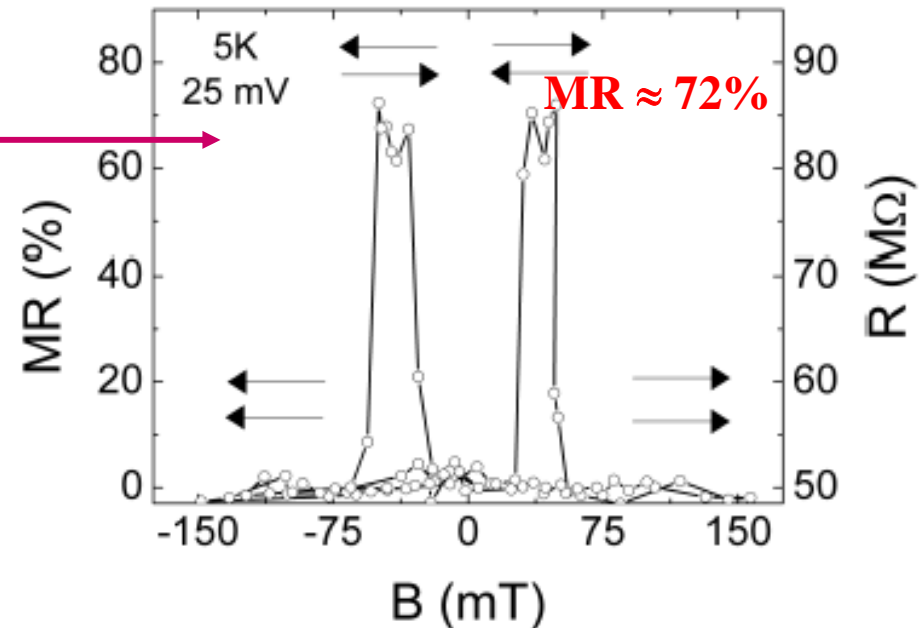
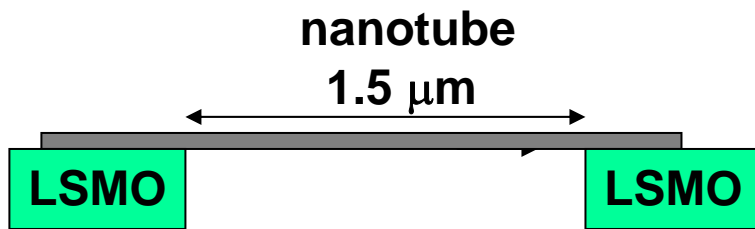
Semiconductor channel:

« Measured effects of the order of **0.1-1%** have been reported for the change in voltage or resistance (between **P** and **AP**).... », from the review article « *Electrical Spin Injection and Transport in Semiconductors* » by **BT Jonker** and **ME Flatté** in *Nanomagnetism* (ed.: **DL Mills** and **JAC Bland**, Elsevier 2006)

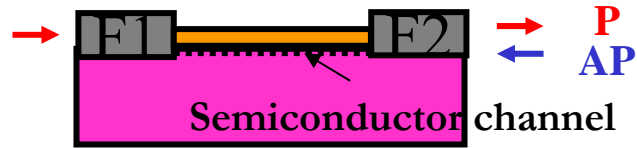
L.Hueso, N.D. Mathur, A.F. et al, Nature 445, 410, 2007

Carbon nanotubes:

$\Delta R/R \approx 60-70\%$, $V_{AP}-V_P \approx 20-60$ mV



Nonmagnetic lateral channel between spin-polarized source and drain



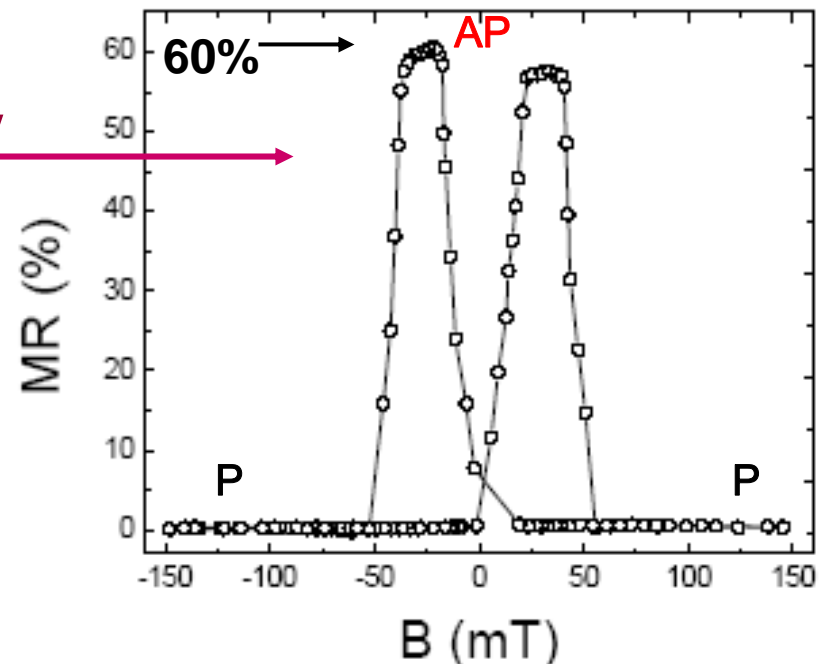
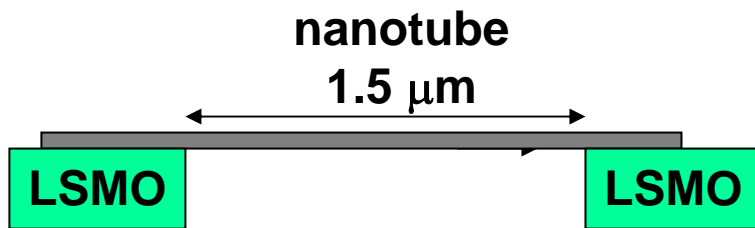
Semiconductor channel:

« Measured effects of the order of **0.1-1%** have been reported for the change in voltage or resistance (between **P** and **AP**).... », from the review article « *Electrical Spin Injection and Transport in Semiconductors* » by **BT Jonker** and **ME Flatté** in *Nanomagnetism* (ed.: **DL Mills** and **JAC Bland**, Elsevier 2006)

L.Hueso, N.D. Mathur, A.F. et al, Nature 445, 410, 2007

Carbon nanotubes:

$\Delta R/R \approx 60-70\%$, $V_{AP}-V_P \approx 20-60$ mV

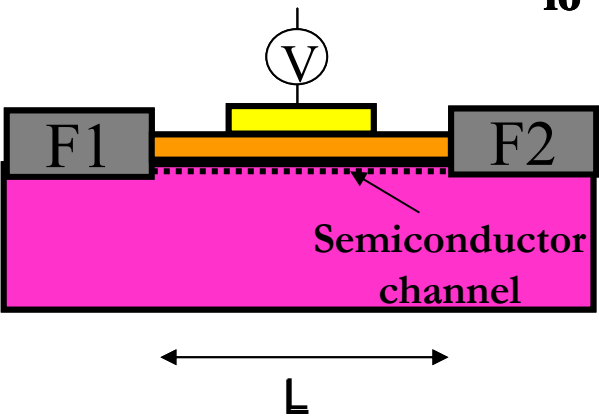
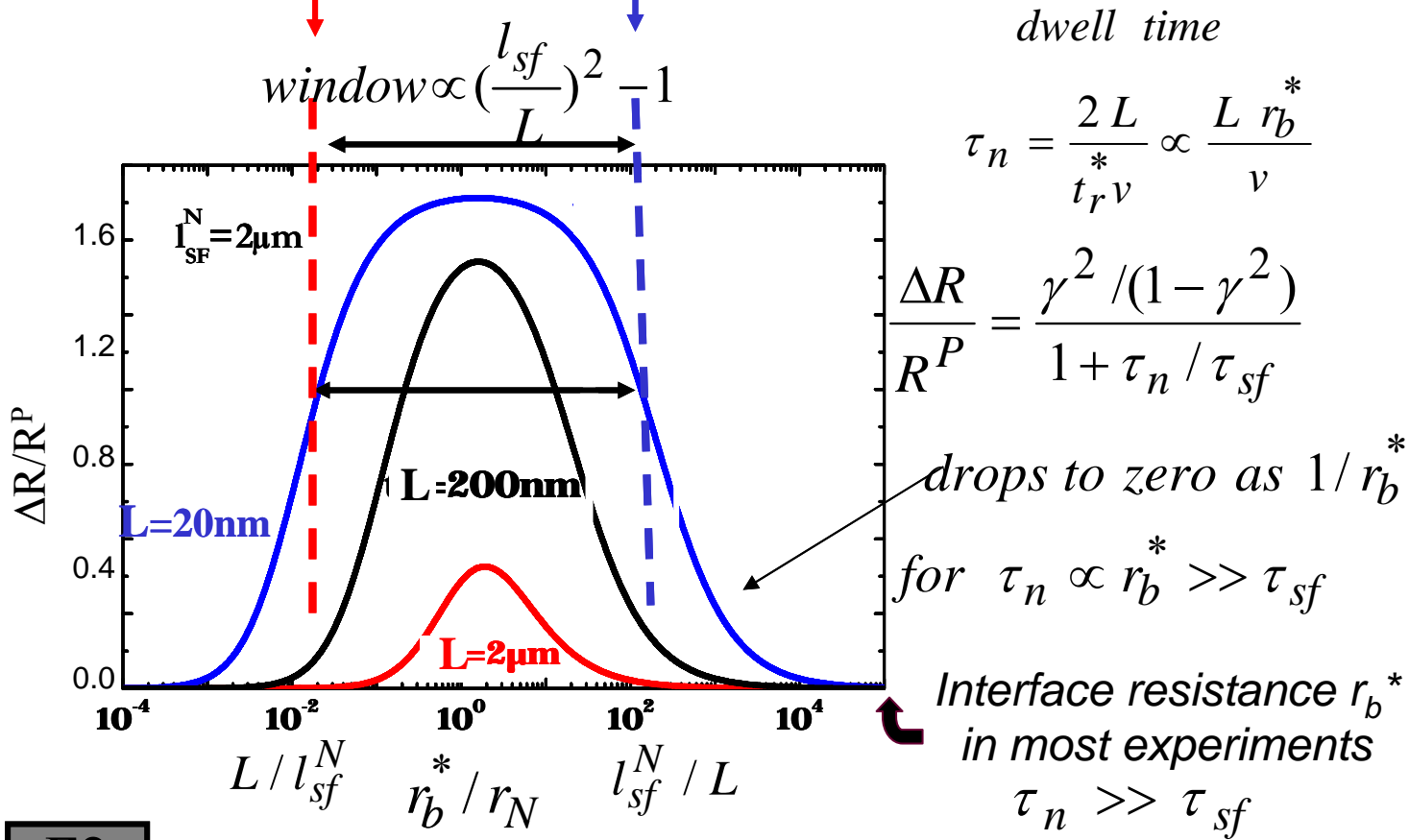


Two interface spin transport problem (diffusive regime)

AF and Jaffrès
PR B 2001
+cond-mat
0612495, +
IEEE
Transactions on
Electronic
Devices.
54,5,921,2007

Condition for spin injection

Condition
dwell time $\tau_n < \text{spin lifetime } \tau_{sf}$



r_b^* = unit area interface resist. $\propto 1/\text{trans.coef } t_r^*$
 γ = spin asymmetry of the interface resistance (calc. with $\gamma = 0.8$)

$$r_N = \rho_N l_{sf}^N$$

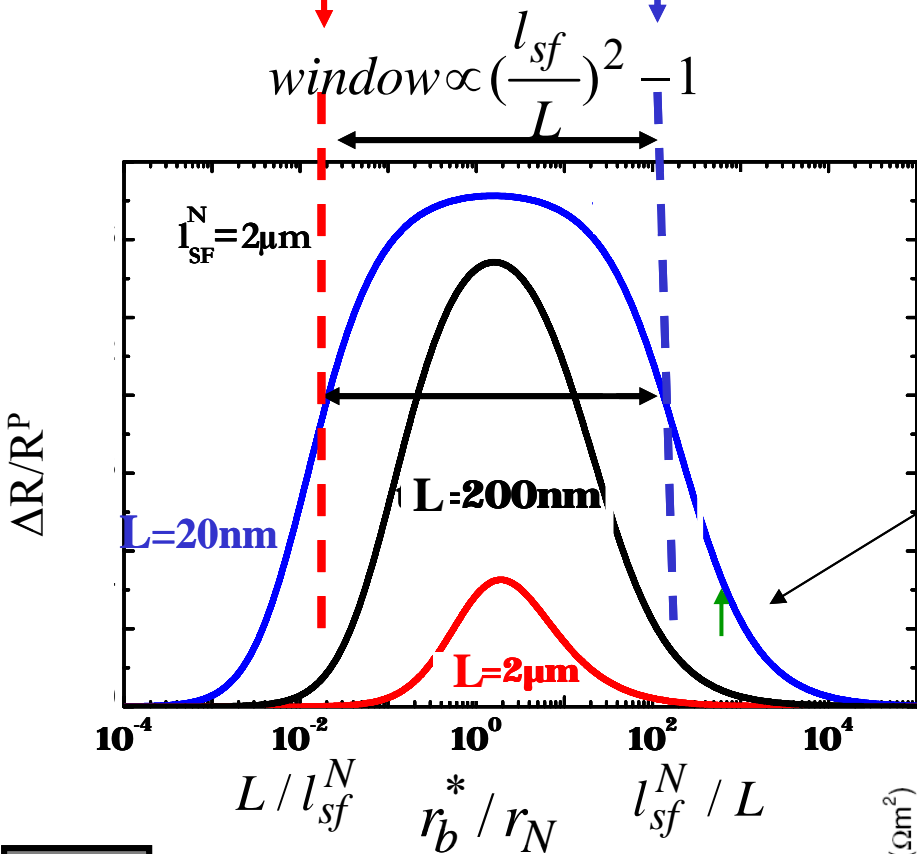
Window only for $l_{sf}(N) > L$

Two interface spin transport problem (diffusive regime)

Condition for spin injection

Condition dwell time $\tau_n < \text{spin lifetime } \tau_{sf}$

AF and Jaffrès
PR B 2001*
+cond-mat
0612495, +
IEEE Tr.El.Dev.*
54,5,921,2007
*calculation. for
Co and GaAs
at RT

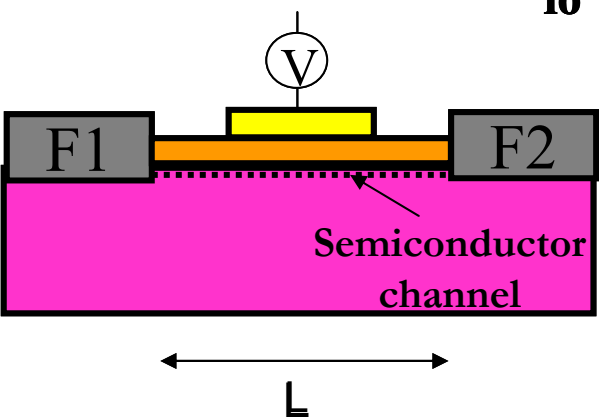


dwell time

$$\tau_n = \frac{2L}{t_r v} \propto \frac{L r_b^*}{v}$$

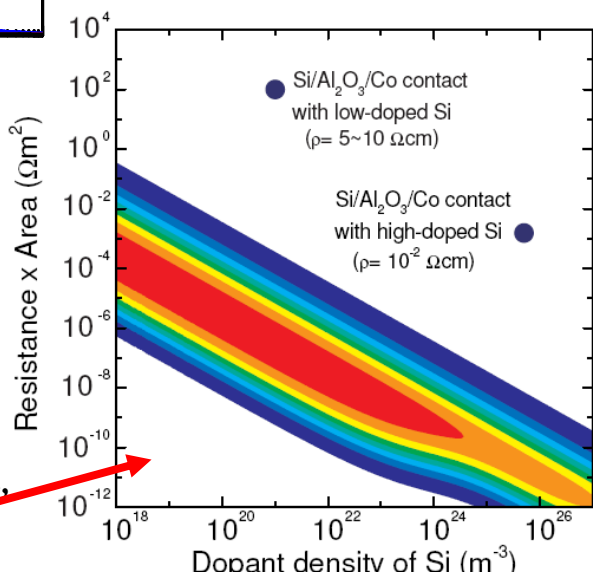
$$\frac{\Delta R}{R^P} = \frac{\gamma^2 / (1 - \gamma^2)}{1 + \tau_n / \tau_{sf}}$$

drops to zero as $1/r_b^*$
for $\tau_n \propto r_b^* \gg \tau_{sf}$



Window only for $l_{sf}(N) > L$

Min, Motihashi, Lodder and Jansen,
Nature Mat. 5, 817, 2006

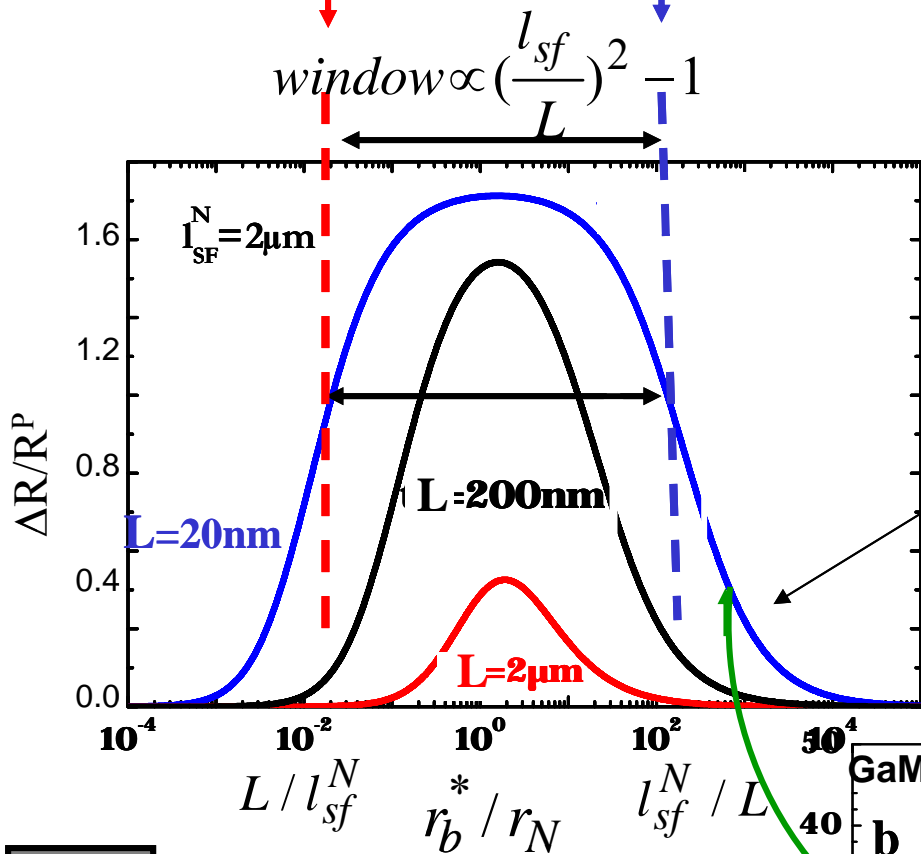


Two interface spin transport problem (diffusive regime)

Condition for spin injection

Condition dwell time $\tau_n < \text{spin lifetime } \tau_{sf}$

AF and Jaffrès
PR B 2001*
+cond-mat
0612495, +
IEEE Tr.El.Dev*.
54,5,921,2007
*calculation. for
Co and GaAs
at RT

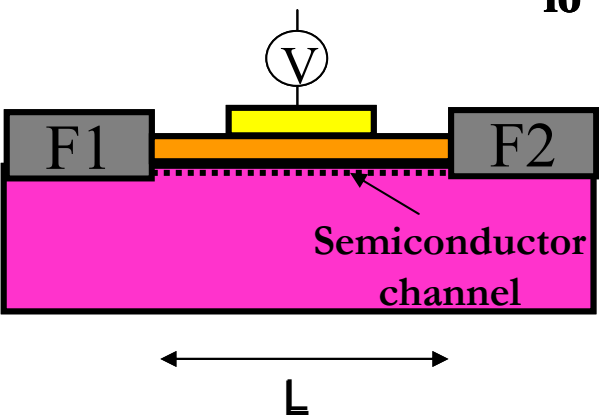


dwell time

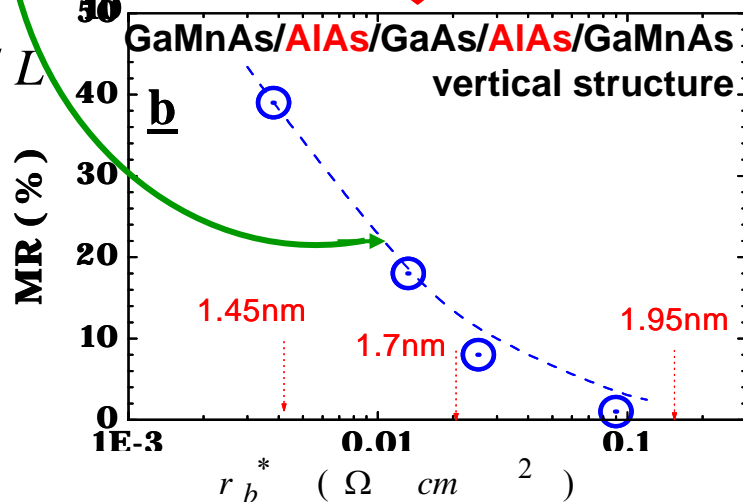
$$\tau_n = \frac{2L}{t_r v} \propto \frac{L r_b^*}{v}$$

$$\frac{\Delta R}{R^P} = \frac{\gamma^2 / (1 - \gamma^2)}{1 + \tau_n / \tau_{sf}}$$

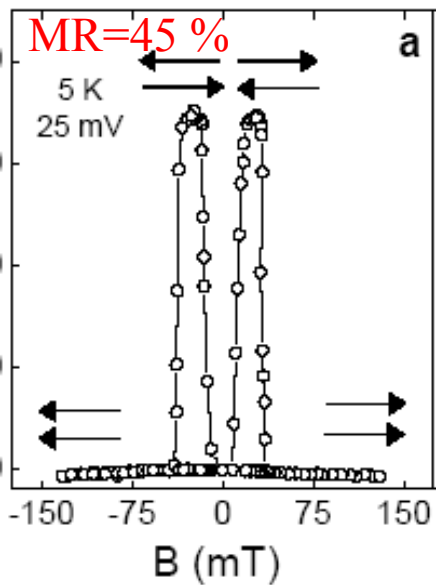
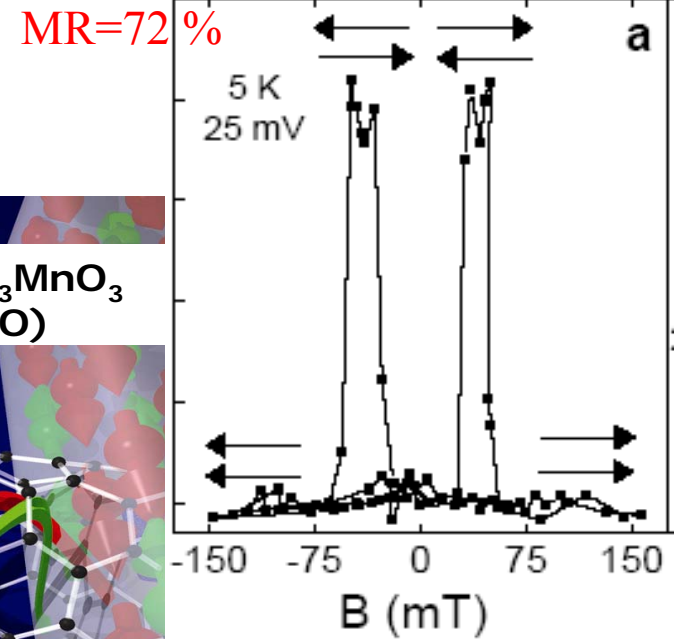
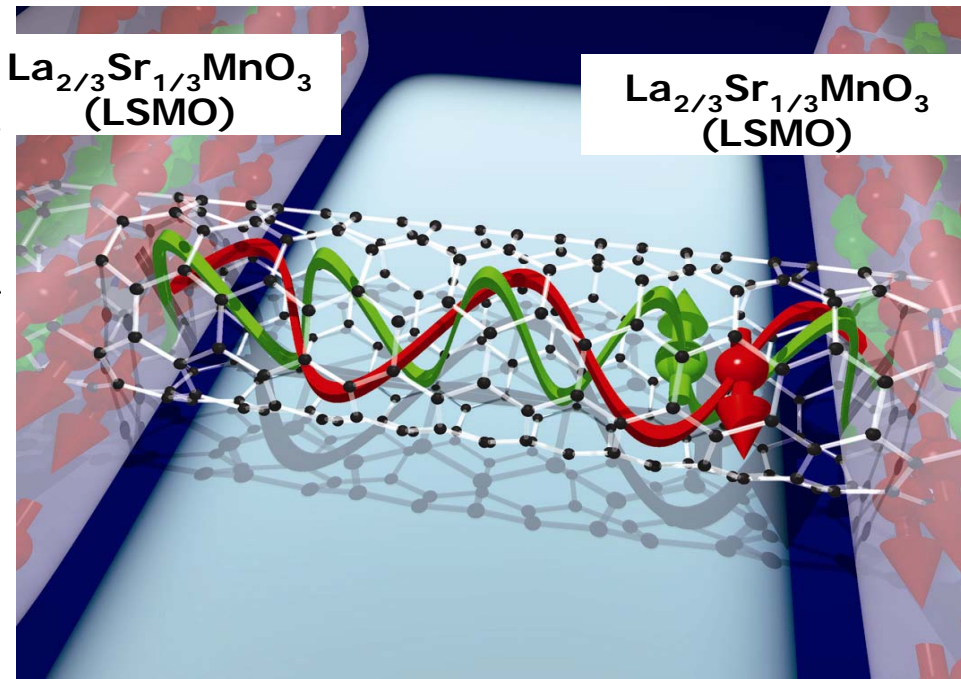
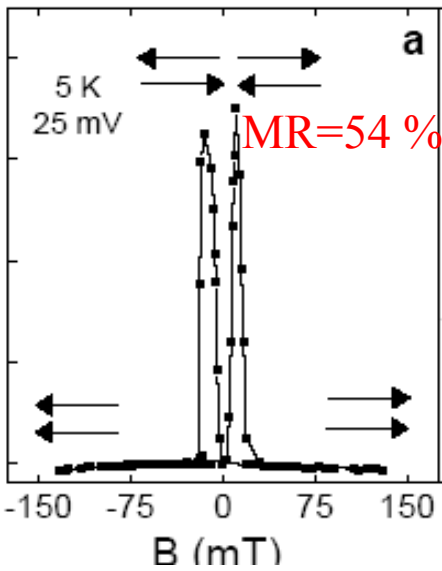
drops to zero as $1/r_b^*$
as in this example
(Mattana, AF et al)



Window only for $l_{sf}(N) > L$

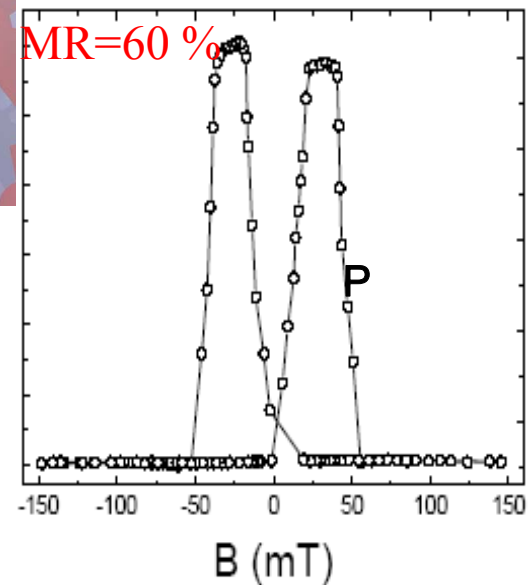


Carbon nanotubes between spin-polarized sources and drains

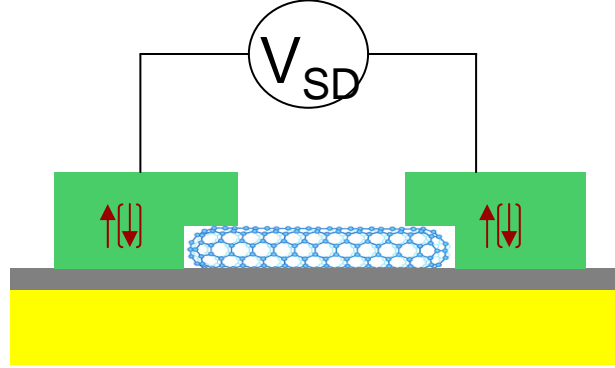


$L \approx 1-2 \mu\text{m}$

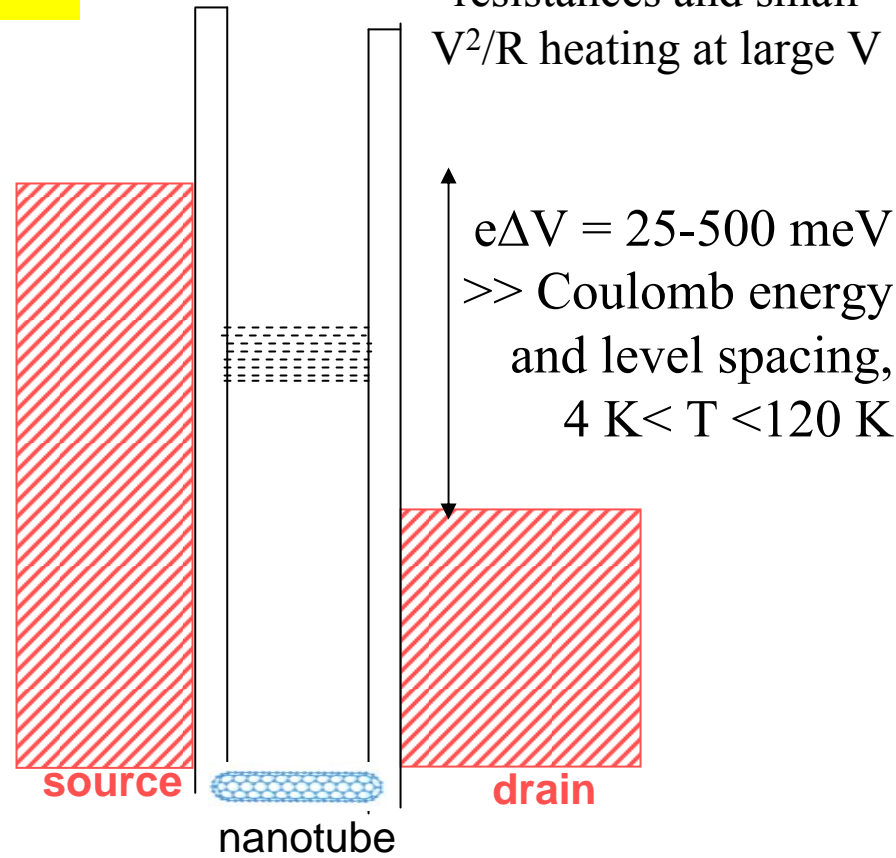
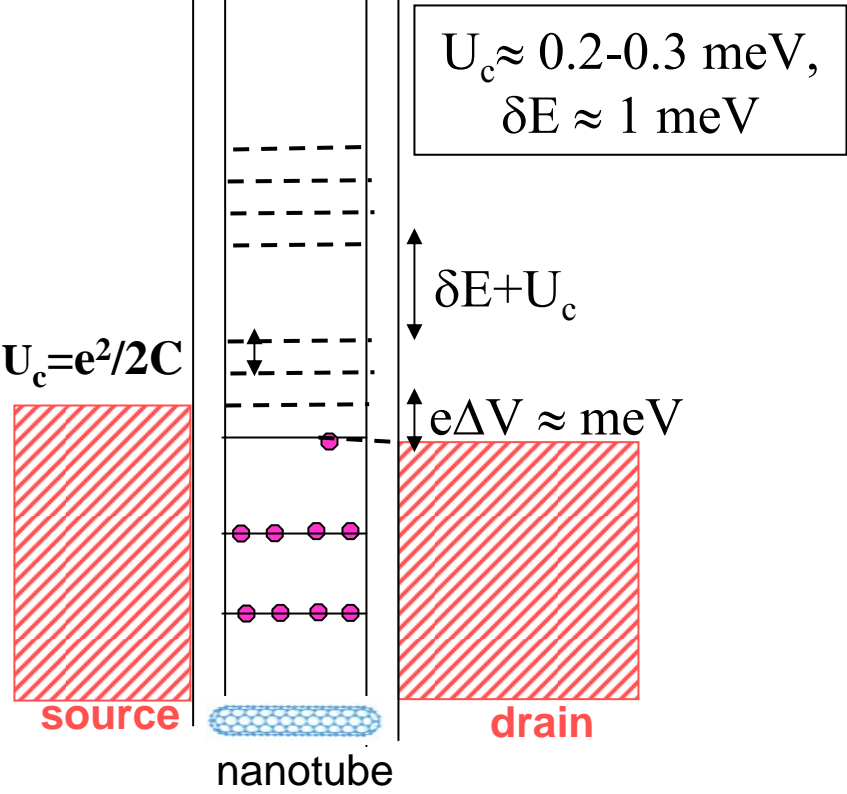
Artist: Takis Kontos



Usual conditions:
experiments at small bias voltage



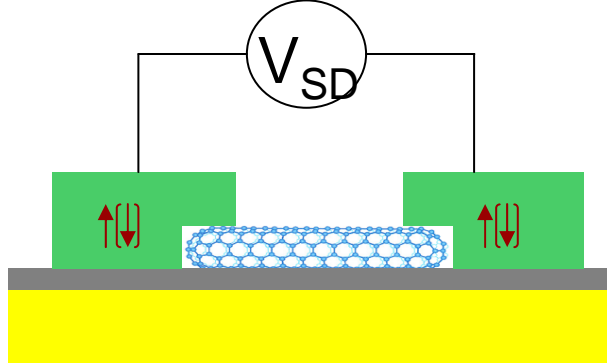
LSMO/CNT/LSMO:
experiments at higher voltage, thanks to relatively large interface resistances and small V^2/R heating at large V



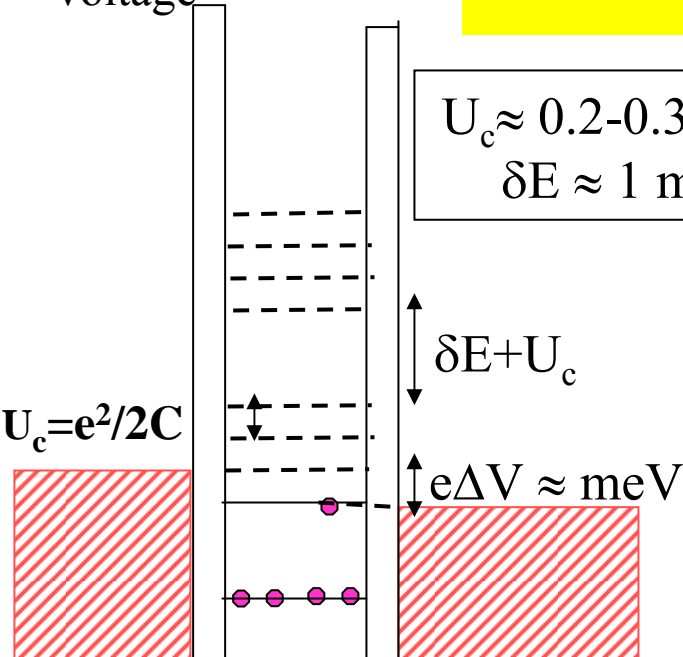
Oscillatory variation of the conductance, different signs of the MR depending on the bias voltage and from sample to sample

Quasi-continuous DOS, same conditions as for semiconducting or metallic channel (also diffusive transport regime)

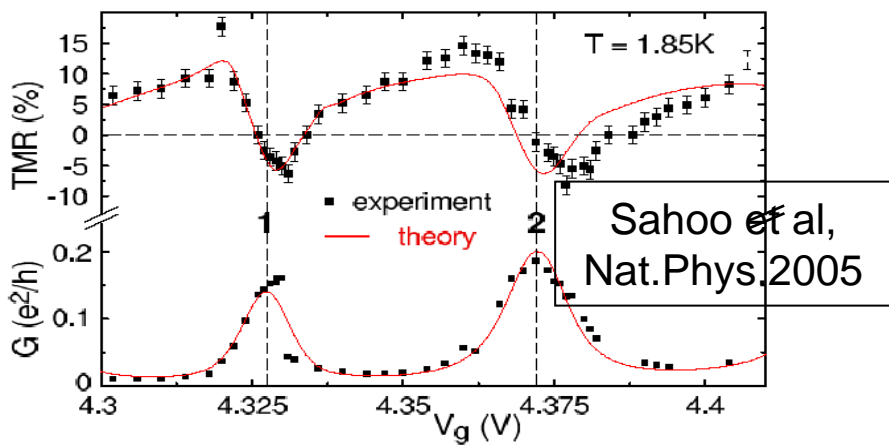
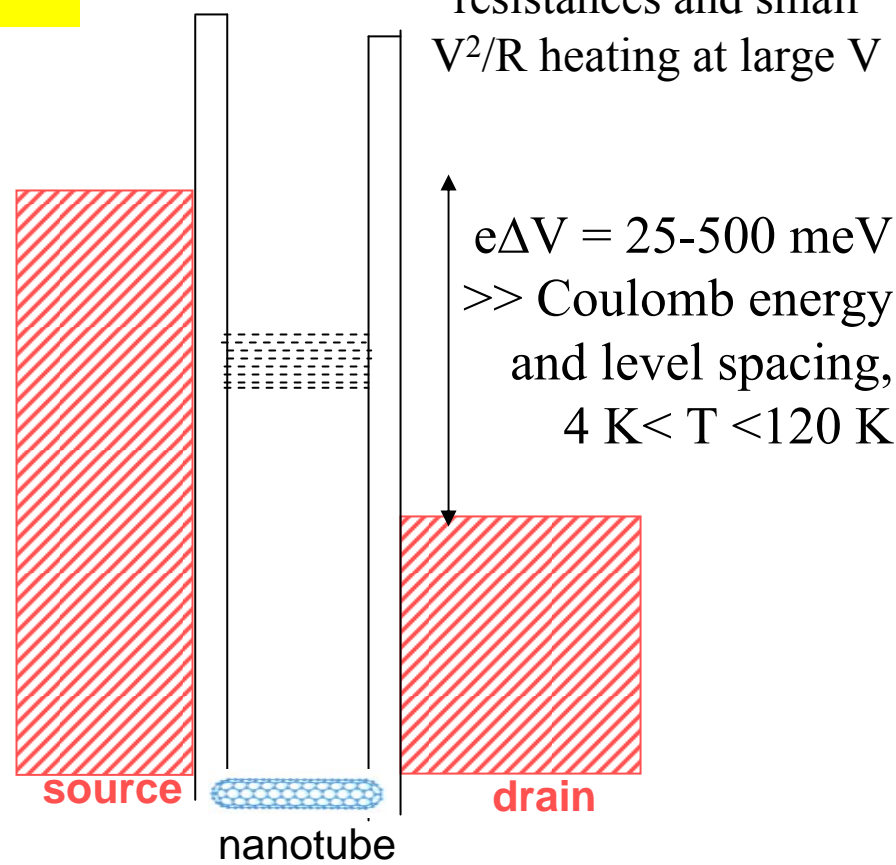
Usual conditions:
experiments at small bias voltage



$U_c \approx 0.2-0.3$ meV,
 $\delta E \approx 1$ meV

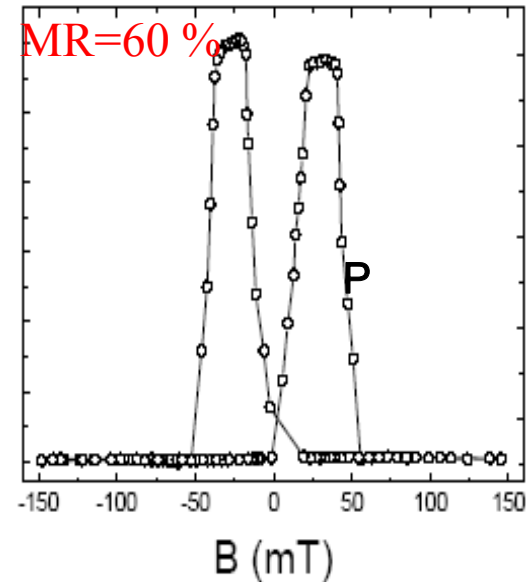
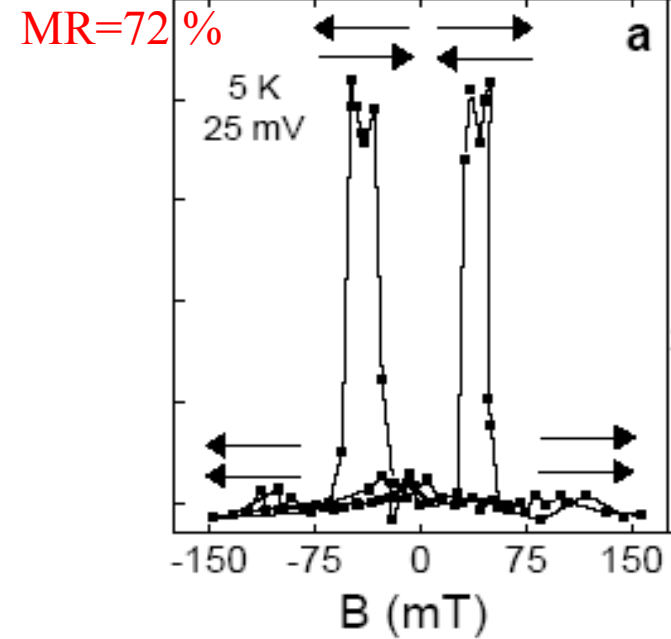
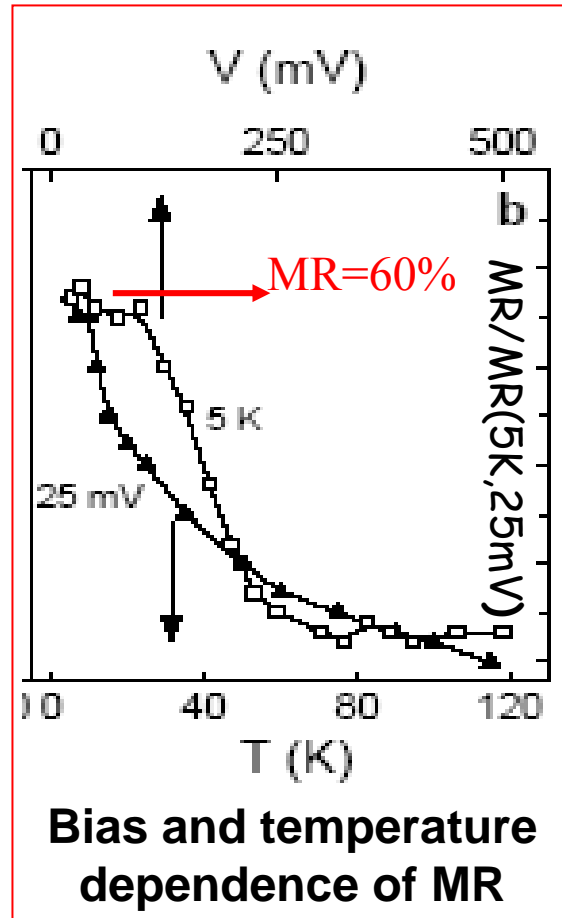
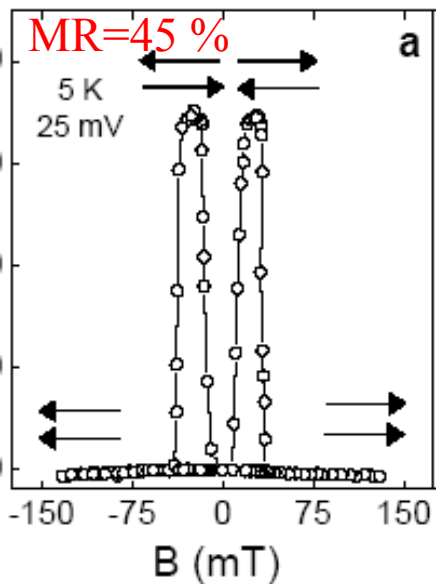
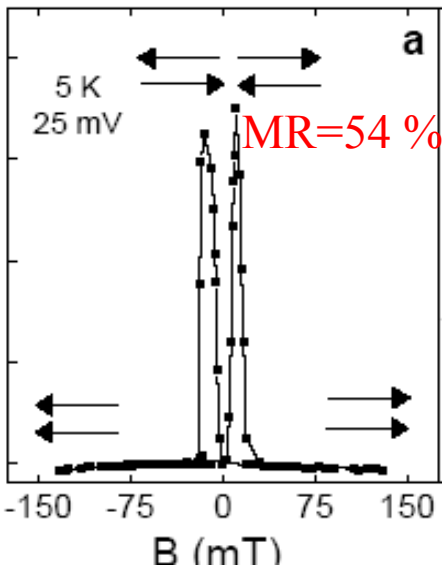


LSMO/CNT/LSMO:
experiments at higher voltage, thanks to relatively large interface resistances and small V^2/R heating at large V



Quasi-continuous DOS, same conditions as for semiconducting or metallic channel (also diffusive transport regime)

Carbon nanotubes between spin-polarized sources and drains



Transport between SP source and drain : τ_n = dwell time, τ_{sf} = spin lifetime, γ = injection SP

: the contrast between P (on) and AP (off), $\frac{\Delta R}{R^P} = \frac{\gamma^2 / (1 - \gamma^2)}{1 + \tau_n / \tau_{sf}}$, is large if $\tau_n < \tau_{sf}$

Nanotubes (also graphene, other molecules) :

small spin - orbit \rightarrow spin lifetime τ_{sf} is long ($\approx 5 - 50\text{ns}$)

*high velocity $v \rightarrow \tau_n = \frac{2L}{v \bar{t}_r}$ can be relatively short (60ns) **

Semiconductors:

τ_{sf} can be as long as in CNT (for $n \approx 10^{16-17} \text{el} / \text{cm}^3$)

but v is smaller \rightarrow long $\tau_n = \frac{2L}{v \bar{t}_r} \gg \tau_{sf}$

with $\tau_n \approx 60\text{ns}^*$
(from interface resist.)

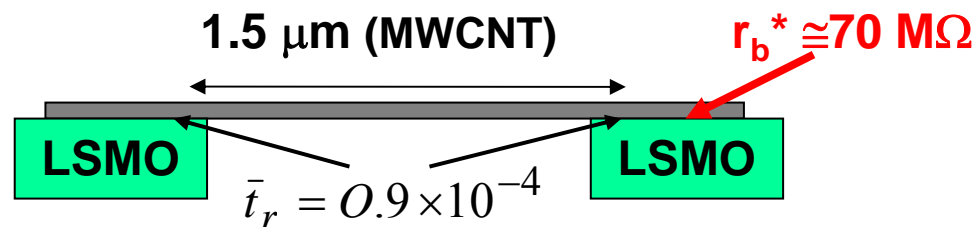
fit with $\tau_{sf} \approx 30\text{ns}$

($l_{sf} = 48\mu\text{m}$) and $\gamma = 0.8$

$\rightarrow \tau_n \approx \tau_{sf}$

(Hueso, AF et al, Nat.07)

* CNT : $\tau_n = 60\text{ns}$ from L , v of CNT and \bar{t}_r derived from interface resistance r_b^*



Transport between SP source and drain : τ_n = dwell time, τ_{sf} = spin lifetime, γ = injection SP

: the contrast between P (on) and AP (off), $\frac{\Delta R}{R^P} = \frac{\gamma^2 / (1 - \gamma^2)}{1 + \tau_n / \tau_{sf}}$, is large if $\tau_n < \tau_{sf}$

Nanotubes (also graphene, other molecules) :

small spin - orbit \rightarrow spin lifetime τ_{sf} is long ($\approx 5 - 50$ ns)

*high velocity $v \rightarrow \tau_n = \frac{2L}{v t_r}$ can be relatively short (60ns) **

Semiconductors:

τ_{sf} can be as long as in CNT (for $n \approx 10^{16-17}$ el / cm³)

but v is smaller \rightarrow long $\tau_n = \frac{2L}{v t_r} \gg \tau_{sf}$

Solution for semiconductors:

shorter L ?, larger transmission t_r ?

- $\tau_n \approx 60$ ns*,
 $\tau_{sf} > 4$ ns if $\gamma < 0.95$
or $\tau_{sf} \approx 30$ ns
($l_{sf} = 48 \mu\text{m}$) for $\gamma = 0.8$
 $\rightarrow \tau_n \approx \tau_{sf}$
(Hueso, AF et al, Nat.07)

Improvement for nanotubes:

slightly larger transmission t_r and
**longer spin lifetime with the spin
polarization directed along the tube**

Nanotubes, graphene..

Next challenge for nanotubes (or graphene...):

spin control by a gate potential

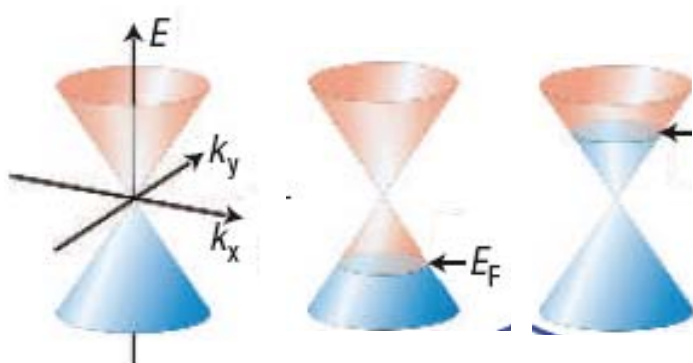
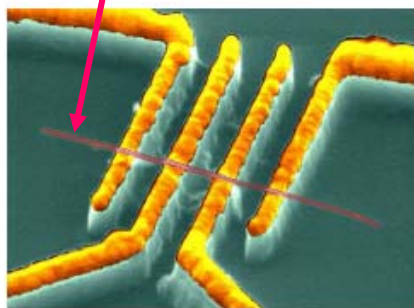
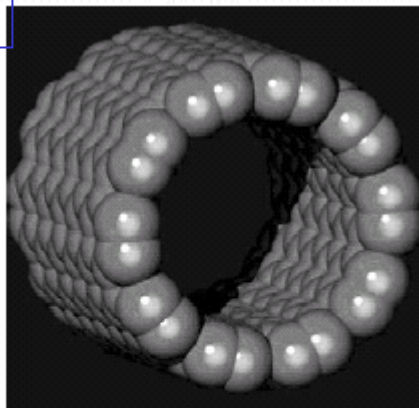
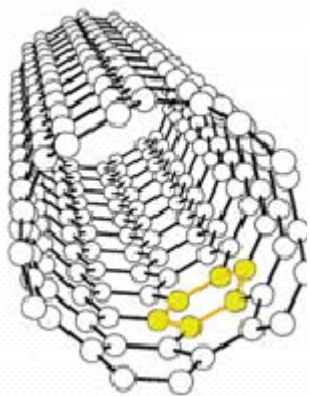
Molecules in general

Promising potential of molecular spintronics

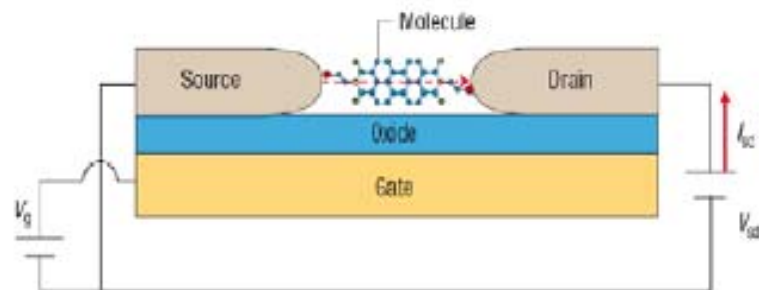
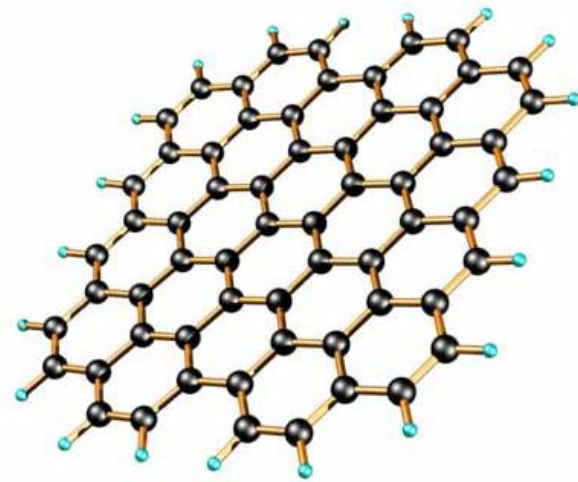
New materials for spintronics (carbon nanotubes, graphene, molecules,)

Examples of new materials

Carbon nanotubes



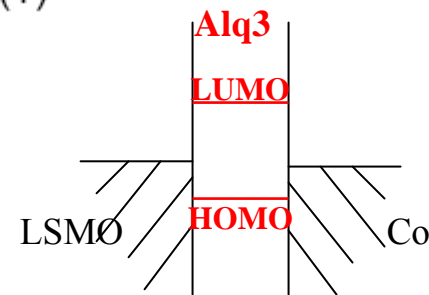
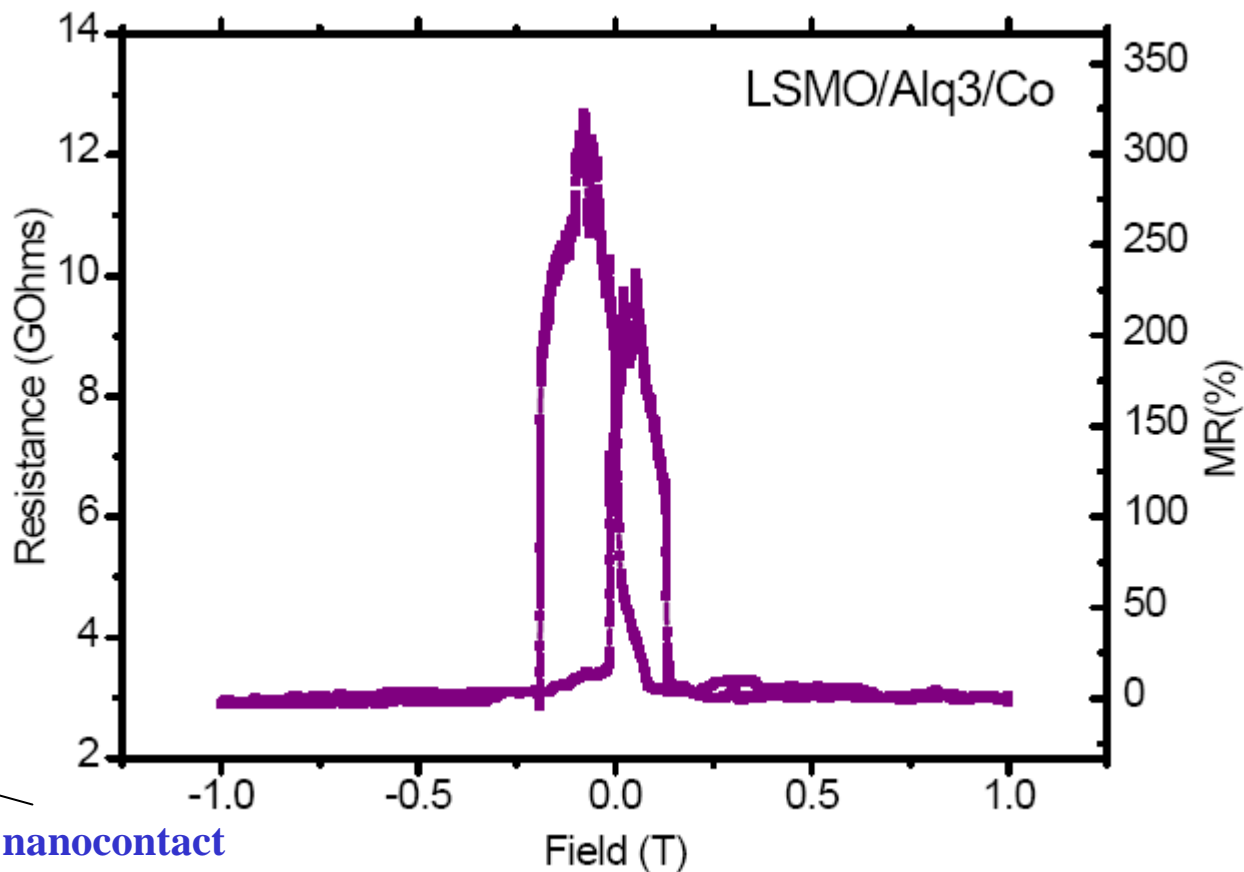
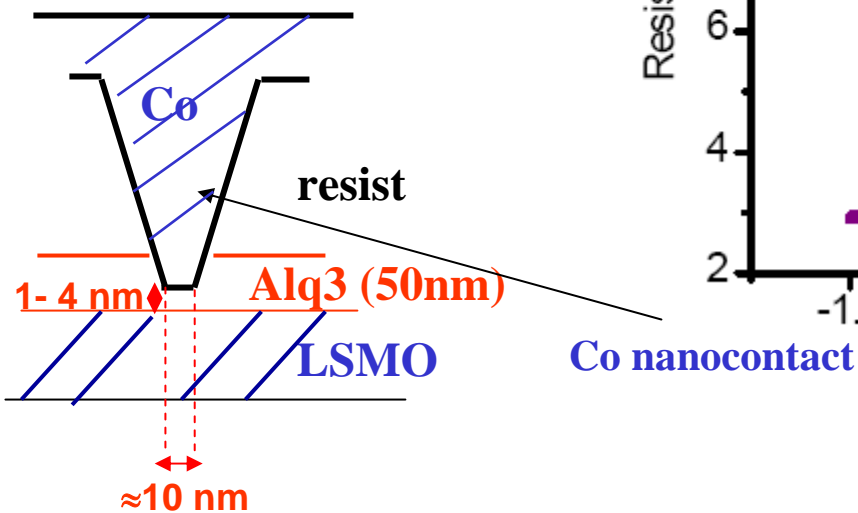
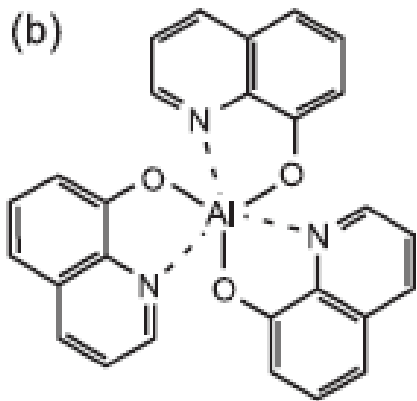
Graphene



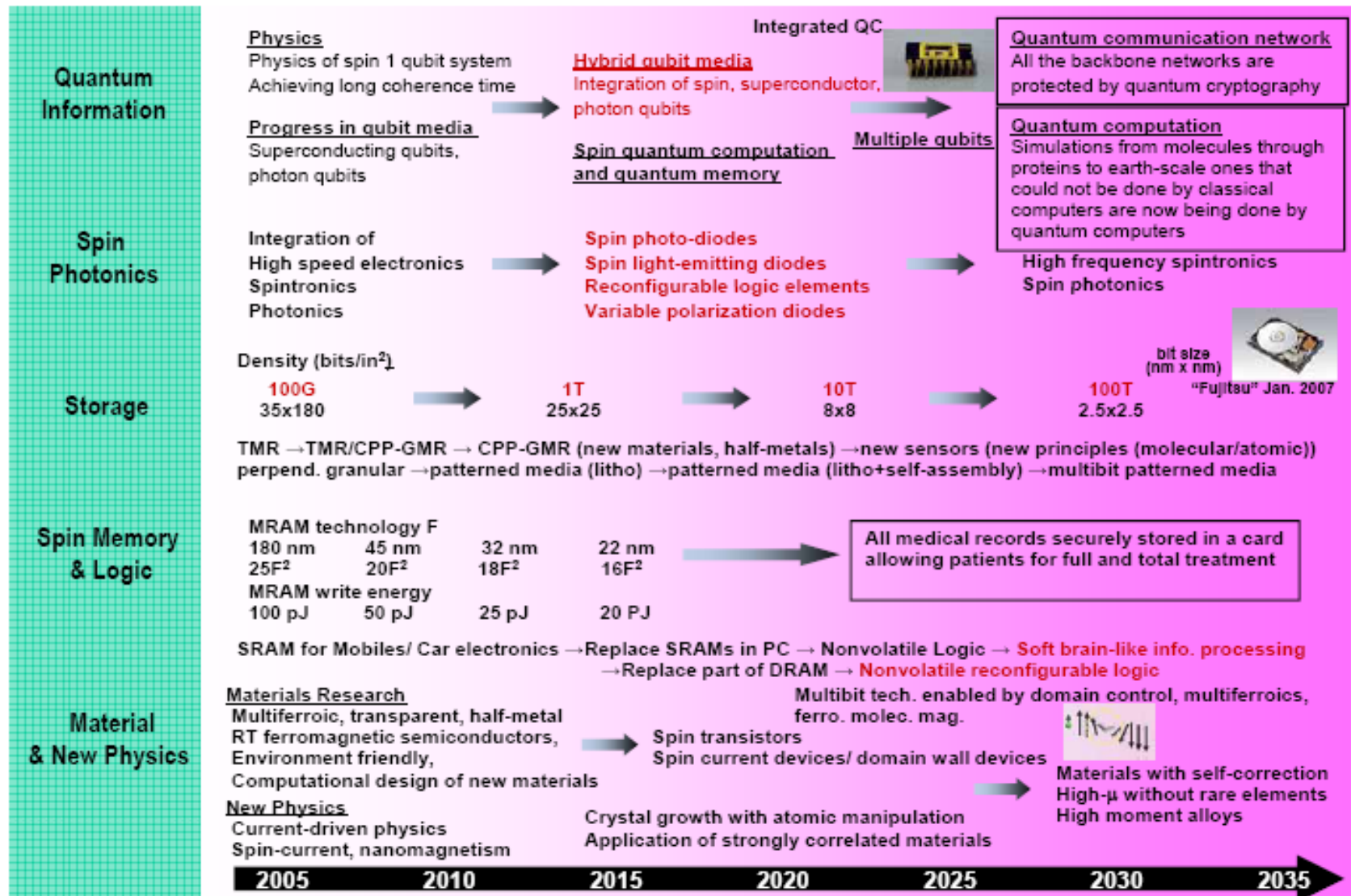
Molecules

MR of LSMO/Alq3/Co structures (preliminary results)

Collaboration CNRS/Thales [C. Barraud, P. Seneor et al) and CNR Bologna (Dediu et al)]



Alq3 = π - conjugated 8-hydroxy-quinoline aluminium



Summary

α Already important applications of GMR/TMR (HDD, MRAM..) and now promising new fields

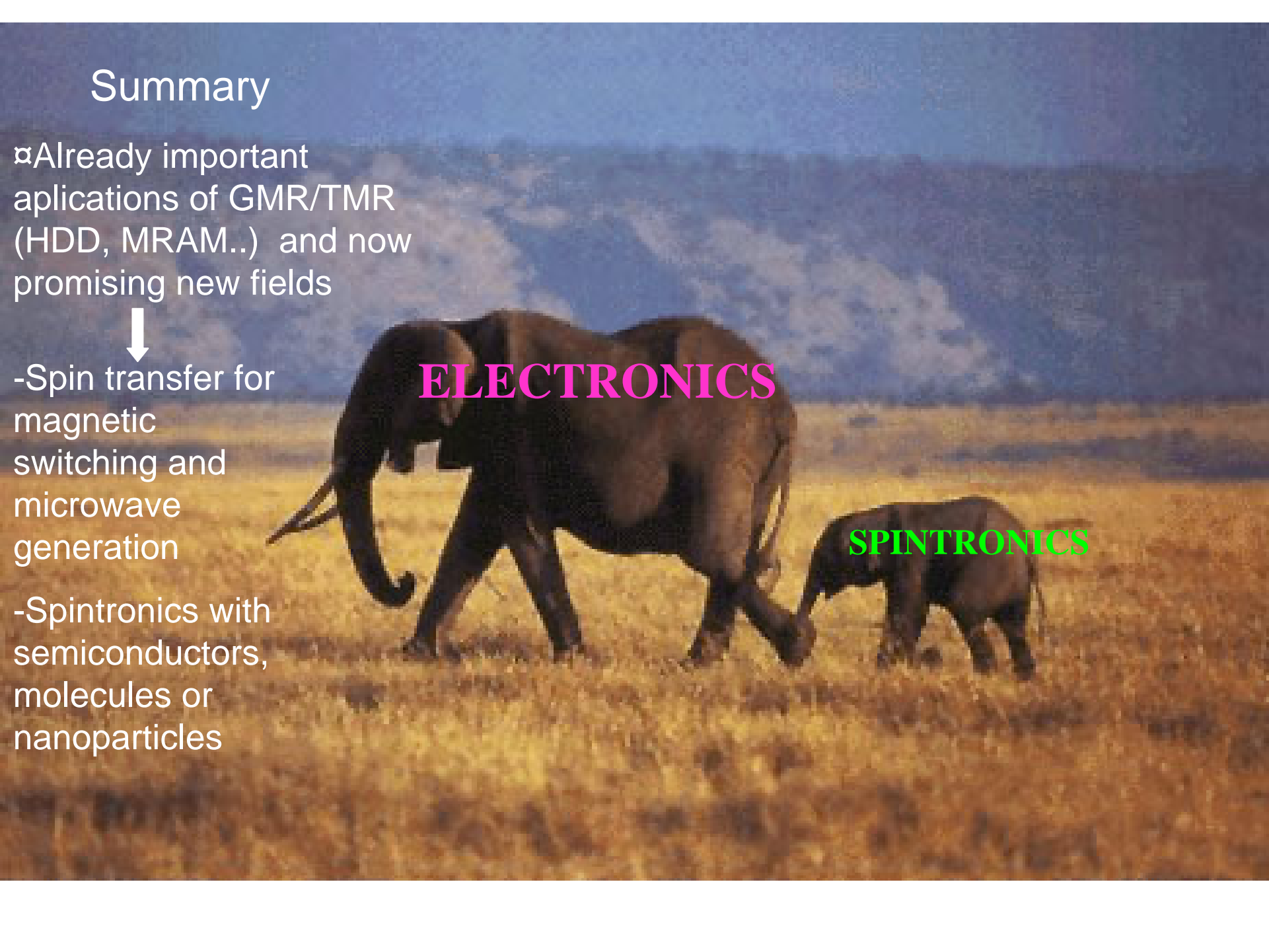


-Spin transfer for magnetic switching and microwave generation

-Spintronics with semiconductors, molecules or nanoparticles

ELECTRONICS

SPINTRONICS



Acknowledgements to

M. Anane, C. Barraud, A. Barthélémy, H. Bea, A. Bernand-Mantel, M. Bibes, O. Boulle, K. Bouzehouane, O. Copi, V. Cros, C. Deranlot, B. Georges, J-M. George, J. Grollier, H. Jaffrès, S. Laribi, J-L. Maurice, R. Mattana, F. Petroff, P. Seneor, M. Tran F. Van Dau, A. Vaurès

Université Paris-Sud and Unité Mixte de Physique CNRS-Thales, Orsay, France

P.M. Levy, New York Un., **A. Hamzic, M. Basletic** Zagreb University

B. Lépine, A. Guivarch and G. Jezequel

Unité PALMS, Université de Rennes , Rennes, France

G. Faini, R. Giraud, A. Lemaître: CNRS-LPN, Marcoussis, France

L. Hueso, N. Mathur, Cambridge

J. Barnas, M. Gimtra, I. Weymann, Poznan University